PCTEST

PCTEST ENGINEERING LABORATORY, INC.

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HEARING AID COMPATIBILITY CERTIFICATE

Applicant Name:

Samsung Electronics, Co. Ltd. 18600 Broadwick St. Rancho Dominguez, CA 90220 USA Date of Testing: March 9 - 10, 2006 Test Site/Location:

PCTEST Lab, Columbia, MD, USA

Test Report Serial No.: HAC.0602210101.A3L

FCC ID: A3LSPHA640S

APPLICANT: SAMSUNG ELECTRONICS, CO. LTD.

Application Type: Certification

FCC Rule Part(s): § 20.19(b), §6.3(v), §7.3(v) **HAC Standard:** ANSI PC63.19-2005 D3.6

FCC Classification: Licensed Transmitter Held to Ear (PCE)

EUT Type: Dual-Band CDMA Phone

Model(s): SPH-A640S

Tx Frequency: 824.70 - 848.31 MHz (CDMA) 1851.25 - 1908.75 MHz (PCS)

Test Device Serial No.: Pre-Production Sample [S/N: AD-004-A]

PC63.19 HAC Rated Category: M3 (RF EMISSIONS)

This wireless portable device has been shown to be hearing-aid compatible under the above rated category, specified in ANSI/IEEE Std. PC63.19 and had been tested in accordance with the specified measurement procedures. Hearing-Aid Compatibility is based on the assumption that all production units will be designed electrically identical to the device tested in this report.

I attest to the accuracy of data. All measurements reported herein were performed by me or were made under my supervision and are correct to the best of my knowledge and belief. I assume full responsibility for the completeness of these measurements and vouch for the qualifications of all persons taking them.

PCTEST certifies that no party to this application has been denied the FCC benefits pursuant to Section 5301 of the Anti-Drug Abuse Act of 1988, 21 U.S.C. 862.

Randy Ortanez President 

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1. INTRODUCTION

On July 10, 2003, the Federal Communications Commission (FCC) adopted new rules requiring wireless manufacturers and service providers to provide digital wireless phones that are compatible with hearing aids. The FCC has modified the exemption for wireless phones under the Hearing Aid Compatibility Act of 1998 (HAC Act) in WT Docket 01-309 RM-8658¹ to extend the benefits of wireless telecommunications to individuals with hearing disabilities. These benefits encompass business, social and emergency communications, which increase the value of the wireless network for everyone. An estimated more than 10% of the population in the United States show signs of hearing impairment and of that fraction, almost 80% use hearing aids. Approximately 500 million people worldwide suffer from hearing loss.

Compatibility Tests Involved:

The standard calls for wireless communications devices to be measured for:

- RF Electric-field emissions
- RF Magnetic-field emissions
- T-coil mode, magnetic-signal strength in the audio band
- T-coil mode, magnetic-signal frequency response through the audio band
- T-coil mode, magnetic-signal and noise articulation index

The hearing aid must be measured for:

- RF immunity in microphone mode
- RF immunity in T-coil mode

In the following tests and results, this report includes the evaluation for a wireless communications device.



Figure 1 Hearing Aid in-vitu

¹ FCC Rule & Order, WT Docket 01-309 RM-8658

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2. TEST SITE LOCATION

2.1 INTRODUCTION

The map at the right shows the location of the PCTEST LABORATORY in Columbia, Maryland. It is in proximity to the FCC Laboratory, the Baltimore-Washington International (BWI) airport, the city of Baltimore and Washington, DC (See Figure 2).

These measurement tests were conducted at the PCTEST Engineering Laboratory, Inc. facility in New Concept Business Park, Guilford Industrial Park, Columbia, Maryland. The site address is 6660-B Dobbin Road, Columbia, MD 21045. The test site is one of the highest points in the Columbia area with an elevation of 390 feet above mean sea level. The site coordinates are 39° 11'15" N latitude and 76° 49' 38" W longitude. The facility is 1.5 miles North of the FCC laboratory, and the ambient signal and ambient signal strength are approximately equal to those of the FCC laboratory. There are no FM or TV transmitters within 15 miles of the site. The detailed description of the measurement facility was found to be in compliance with the requirements of § 2.948 according to ANSI C63.4 on October 19, 2002.



Figure 2
Map of the Greater Baltimore and Metropolitan
Washington, D.C. area

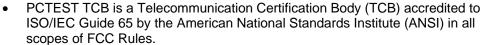
2.2 Test Facility / NVLAP Accreditation:

Measurements were performed at an independent accredited PCTEST Engineering Lab located in Columbia, MD 21045, U.S.A.



- PCTEST facility is an FCC registered (PCTEST Reg. No. 90864) test facility with the site description report on file and has met all the requirements specified in Section 2.948 of the FCC Rules and Industry Canada (IC 2451).
- PCTEST Lab is accredited to ISO 17025 by U.S. National Institute of Standards and Technology (NIST) under the National Voluntary Laboratory Accreditation Program (NVLAP Lab code: 100431-0) in EMC, FCC and Telecommunications.
- PCTEST Lab is accredited to ISO 17025 by the American Association for Laboratory Accreditation (A2LA) in Specific Absorption Rate (SAR) testing, CTIA Test Plans, and wireless testing for FCC, HAC, CTIA OTA and Industry Canada Rules.





- PCTEST facility is an IC registered (IC-2451) test laboratory with the site description on file at Industry Canada.
- PCTEST is a CTIA Authorized Test Laboratory (CATL) in AMPS and CDMA mobile phones.



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3. EUT DESCRIPTION



FCC ID: A3LSPHA640S

Manufacturer: Samsung Electronics, Co. Ltd.

18600 Broadwick St.

Rancho Dominguez, CA 90220 USA

Trade Name: Samsung
Model(s): SPH-A640S
Serial Number: AD-004-A

Tx Frequencies: 824.70 - 848.31 MHz (CDMA)

1851.25 - 1908.75 MHz (PCS)

Antenna Configurations: Fixed Antenna

Maximum Conducted Power (EMC/SAR): Maximum Conducted

 $25.0~\mathrm{dBm}~(\mathrm{CDMA}),\,25.0~\mathrm{dBm}~(\mathrm{PCS})$

Power (HAC):

25.0 dBm (CDMA), 25.0 dBm (PCS)

HAC Test Configurations: CDMA, Channels 1013, 384, 777

PCS, Channels 25, 600, 1175

FCC Classification: Licensed Transmitter Held to Ear (PCE)

EUT Type: Dual-Band CDMA Phone



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4. ANSI/IEEE PC63.19 PERFORMANCE CATEGORIES

I. RF EMISSIONS

The ANSI Standard presents performance requirements for acceptable interoperability of hearing aids with wireless communications devices. When these parameters are met, a hearing aid operates acceptably in close proximity to a wireless communications device.

Category	ory Hearing aid RF Parameters		Telephone	e RF Parameters
Near field Category	E-field immunity CW dB(V/m)	H-field immunity CW dB(A/m)	E-field emissions CW dB(V/m)	H-field emissions CW dB(A/m)
M1	30.0 to 35.0	−23.0 to −18.0	46 to 51 + 0.5 x AWF	-4.4 to 0.6 +0.5 x AWF
M2	35.0 to 40.0	-18.0 to -13.0	41 to 46 + 0.5 x AWF	−9.4 to −4.4 +0.5 x AWF
M3	40.0 to 45.0	-13.0 to -8.0	36 to 41 + 0.5 x AWF	−14.4 to −9.4 +0.5 x AWF
M4	> 45.0	> -8.0	< 36 + 0.5 x AWF	<-14.4 + 0.5 x AWF

Table 6.1

Hearing aid and WD near-field categories as defined in draft ANSI PC63.19. During testing, the hearing aid must maintain an input-referenced interference level of less than 55 dB and a gain compression of less than 6 dB.

II. ARTICULATION WEIGHTING FACTOR (AWF)

Standard	Technology	Articulation Weighing Factor (AWF)
T1/T1P1/3GPP	UMTS (WCDMA)	0
IS-95	CDMA	0
iDEN™	TDMA (22 and 11 Hz)	0
J-STD-007	GSM (217 Hz)	-5

Table 6.2

AWF has been developed from information presented to the committee regarding the interference potential of the various modulation types according to ANSI PC63.19

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5. SYSTEM SPECIFICATIONS

ER3DV6 E-Field Probe Description

Construction: One dipole parallel, two dipoles normal to probe axis

Built-in shielding against static charges

Calibration: In air from 100 MHz to 3.0 GHz

(absolute accuracy ±6.0%, k=2)

Frequency: 100 MHz to > 6 GHz;

Linearity: ± 0.2 dB (100 MHz to 3 GHz)

Directivity ± 0.2 dB in air (rotation around probe axis)

± 0.4 dB in air (rotation normal to probe axis)

Dynamic Range 2 V/m to > 1000 V/m

(M3 or better device readings fall well below diode

compression point)

Linearity: $\pm 0.2 \text{ dB}$

Dimensions Overall length: 330 mm (Tip: 16 mm)

Tip diameter: 8 mm (Body: 12 mm)

Distance from probe tip to dipole centers: 2.5 mm



Figure 3
E-field Free-space
Probe

H3DV6 H-Field Probe Description

Construction: Three concentric loop sensors with 3.8 mm loop diameters

Resistively loaded detector diodes for linear response

Built-in shielding against static charges

Frequency: 200 MHz to 3 GHz (absolute accuracy \pm 6.0%, k=2);

Output linearized

Directivity: ± 0.25 dB (spherical isotropy error)

Dynamic Range: 10 mA/m to 2 A/m at 1 GHz

(M3 or better device readings fall well below diode

compression point)

Dimensions: Overall length: 330 mm (Tip: 40 mm)

Tip diameter: 6 mm (Body: 12 mm)

Distance from probe tip to dipole centers: 3 mm

E-Field < 10% at 3 GHz (for plane wave)

Interference:



Figure 4 H-Field Free-space Probe

Probe Tip Description

HAC field measurements take place in the close near field with high gradients. Increasing the measuring distance from the source will generally decrease the measured field values (in case of the validation dipole approx. 10% per mm).

Magnetic field sensors are measuring the integral of the H-field across their sensor area surrounded by the loop. They are calibrated in a precise, homogeneous field. When measuring a gradient field, the result will be very close to the field in the center of the loop which is equivalent to the value of a homogeneous field equivalent to the center value. But it will be different from the field at the border of the loop.

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Consequently, two sensors with different loop diameters - both calibrated ideally - would give different results when measuring from the edge of the probe sensor elements. The behavior for electrically small E-field sensors is equivalent. See below for distance plots from a WD which show the conservative nature of field readings at the probe element center vs. measurements at the sensor end:

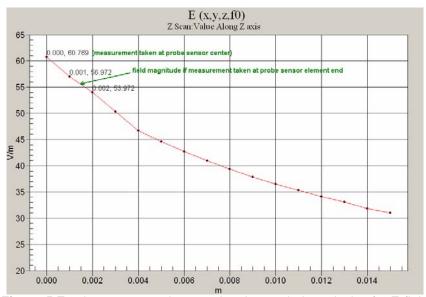


Figure 5 Z-axis scan at maximum point above wireless device for E-field

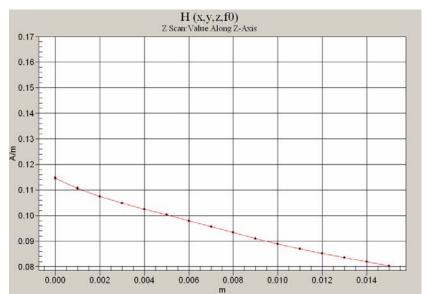
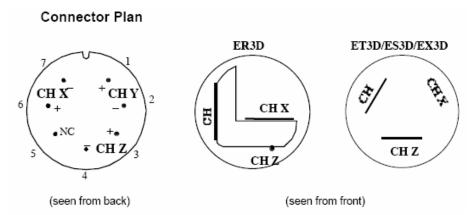


Figure 6 Z-Axis Scan at maximum point above wireless device for H-field

The magnetic field loops of the H3D probes are concentric, with the center 3mm from the tip for H3DV6. Their radius is 1.9mm.

The electric field probes have a more irregular internal geometry because it is physically not possible to have the 3 orthogonal sensors situated with the same center. The effect of the different sensor centers is accounted for in the HAC uncertainty budget ("sensor displacement"). Their geometric center is at 2.5mm from the tip, and the element ends are 1.1mm closer to the tip.

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The antistatic shielding inside the probe is connected to the probe connector case.

It is recommended to connect the probes with the amplifier using a short and well shielded cable and to connect the cable shielding with the connector case.

Instrumentation Chain

Equation 1 Conversion of Connector Voltage u_i to E-Field E_i

$$E_i = \sqrt{\frac{u_i + (u_i^2 \cdot CF)/(DCP)}{Norm_i \cdot ConvF}}$$

whereby

E: electric field in V/m

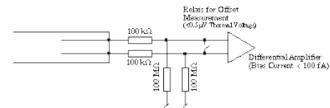
 u_i : voltage of channel i at the connector in μV $Norm_i$: sensitivity of channel i in $\mu V/(V/m)^2$

ConvF: enhancement factor in liquid (ConvF=1 for Air)

DCP: diode compression point in µV

CF: signal crest factor (peak power/average power)

Conditions of Calibration



Please note:

- a lower input impedance of the amplifier will result in different sensitivity factors Norm, and DCP
- larger bias currents will cause higher offset

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Probe Response to Frequency

The E-field sensors have inherently a very flat frequency response. They are calibrated with a number of frequencies resulting in a common calibration factor, with the frequency behavior documented in the calibration certificate (See also below).

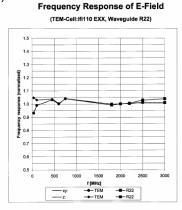


Figure 7 E-Field Probe Frequency Response

H-field sensors have a frequency dependent sensitivity which is evaluated for a series of frequencies also visible in the probe calibration certificate. The calibration factors result from a fitting algorithm. The proper conversion is calculated by the DASY4 software depending on the frequency setting in the procedure. See below for H-field frequency response:

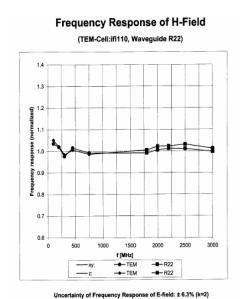


Figure 8 H-Field Probe Frequency Response

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Conversion to Peak

Peak is defined as Peak Envelope Power. All raw measurements from the HAC measurement system are RMS values. The DASY4 system incorporates the crest factor of the signal in the computation of the RMS values (See Equation 1). Although the software also has capability to estimate the peak field by applying a square root of crest factor value to the readings, the probe modulation factor was applied manually instead per PC63.19 in the measurement tables in this report. The equation to convert the raw measurements in the data tables are:

Peak Field = 20·log (Raw · PMF)

Where:

Peak Field = Peak field (in dBV/m or dBA/m)

Raw = Raw field measurement from the measurement system (in V/m or A/m).

PMF = Probe Modulation Factor (in linear units).

SPEAG Robotic System

E-field and H-field measurements are performed using the DASY4 automated dosimetric assessment system. The DASY4 is made by Schmid & Partner Engineering AG (SPEAG) in Zurich, Switzerland and consists of high precision robotics system (Staubli), robot controller, Pentium 4 computer, near-field probe, probe alignment sensor, and the HAC phantom. The robot is a six-axis industrial robot performing precise movements to position the probe to the location (points) of maximum electromagnetic field (EMF).



Figure 9 SPEAG Robotic System



Figure 10
PCTEST Lab Acoustics Facility

System Hardware

A cell controller system contains the power supply, robot controller, teach pendant (Joystick), and a remote control used to drive the robot motors. The PC consists of the Gateway Pentium 4 2.53 GHz computer with Windows XP system and RF Measurement Software DASY4 v4.5 (with HAC Extension), A/D interface card, monitor, mouse, and keyboard. The Staubli Robot is connected to the cell controller to allow software manipulation of the robot. A data acquisition electronic (DAE) circuit that performs the signal amplification, signal multiplexing, AD-conversion, offset measurements, mechanical surface detection, collision detection, etc. is connected to the Electro-optical coupler

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(EOC). The EOC performs the conversion from the optical into digital electric signal of the DAE and transfers data to the PC plug-in card.

System Electronics

The DAE consists of a highly sensitive electrometer-grade preamplifier with auto-zeroing, a channel and gain-switching multiplexer, a fast 16 bit AD-converter and a command decoder and control logic unit. Transmission to the PC-card is accomplished through an optical downlink for data and status information and an optical uplink for commands and clock lines. The mechanical probe mounting device includes two different sensor systems for frontal and sidewise probe contacts. They are also used for mechanical surface detection and probe collision detection. The robot uses its own controller with a built in VME-bus computer.

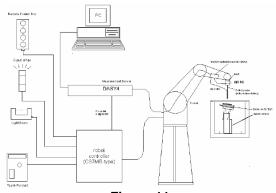


Figure 11
SPEAG Robotic System Diagram

DASY4 Instrumentation Chain

The first step of the evaluation is a linearization of the filtered input signal to account for the compression characteristics of the detector diode. The compensation depends on the input signal, the diode type and the DC-transmission factor from the diode to the evaluation electronics. If the exciting field is pulsed, the crest factor of the signal must be known to correctly compensate for peak power. The formula for each channel can be given as:

		$V_i = U_i + U_i^2 \cdot \frac{cf}{dcp_i}$	
with	$V_i \\ U_i \\ cf \\ dcp_i$	 = compensated signal of channel i = input signal of channel i = crest factor of exciting field = diode compression point 	(i = x, y, z) (i = x, y, z) (DASY parameter) (DASY parameter)

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From the compensated input signals the primary field data for each channel can be evaluated:

E – field
probes :
$$E_i = \sqrt{\frac{V_i}{Norm_i \cdot ConvF}}$$

$$H$$
 – field
probes : $H_i = \sqrt{V_i} \cdot \frac{a_{i0} + a_{i1}f + a_{i2}f^2}{f}$

with
$$V_i$$
 = compensated signal of channel i (i = x, y, z

 $Norm_i$ = sensor sensitivity of channel i $\mu V/(V/m)^2$ for E-field Probes

= sensitivity enhancement in solution

 a_{ij} = sensor sensitivity factors for H-field probes

f = carrier frequency [GHz]

ConvF

 E_i = electric field strength of channel i in V/m H_i = magnetic field strength of channel i in A/m

The RSS value of the field components gives the total field strength (Hermitian magnitude):

$$E_{tot} = \sqrt{E_x^2 + E_y^2 + E_z^2}$$

The primary field data are used to calculate the derived field units.

The measurement/integration time per point, as specified by the system manufacturer is >500 ms.

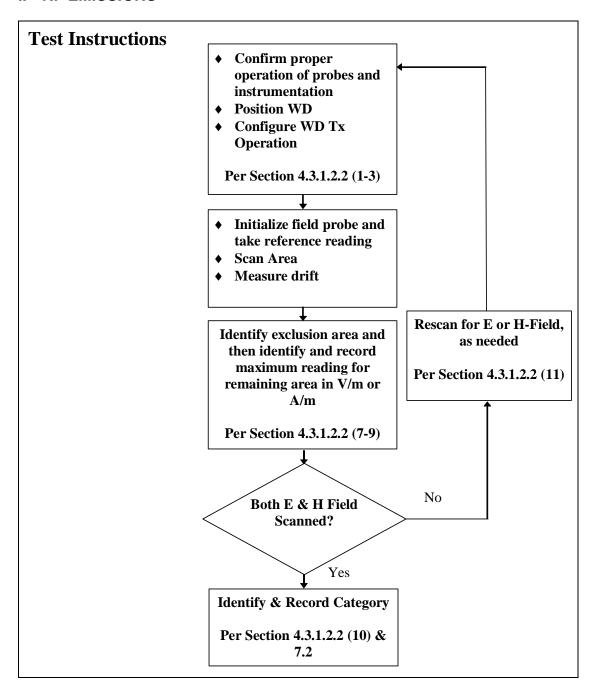
The signal response time is evaluated as the time required by the system to reach 90% of the expected final value after an on/off switch of the power source with an integration time of 500 ms and a probe response time of <5 ms. In the current implementation, DASY4 waits longer than 100 ms after having reached the grid point before starting a measurement, i.e., the response time uncertainty is negligible.

If the device under test does not emit a CW signal, the integration time applied to measure the electric field at a specific point may introduce additional uncertainties due to the discretization. The tolerances for the different systems had the worst-case of 2.6%.

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6. TEST PROCEDURE

I. RF EMISSIONS



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Test Setup

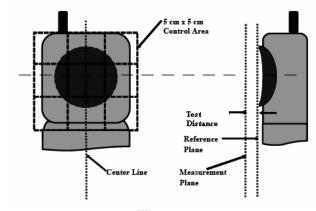


Figure 12
E/H-Field Emissions Test Setup Diagram (See Test Photographs for actual WD scan grid overlay)

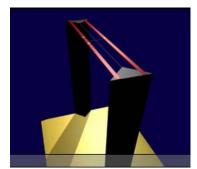


Figure 13 HAC Phantom

RF Emissions Test Procedure:

The following illustrate a typical RF emissions test scan over a wireless communications device:

- 1. Proper operation of the field probe, probe measurement system, other instrumentation, and the positioning system was confirmed.
- 2. WD is positioned in its intended test position, acoustic output point of the device perpendicular to the field probe.
- 3. The WD operation for maximum rated RF output power was configured and confirmed with the base station simulator, at the test channel and other normal operating parameters as intended for the test. The battery was ensured to be fully charged before each test.
- 4. The center sub-grid was centered over the center of the acoustic output (also audio band magnetic output, if applicable). The WD audio output was positioned tangent (as physically possible) to the measurement plane.
- 5. A surface calibration was performed before each setup change to ensure repeatable spacing and proper maintenance of the measurement plane using the HAC Phantom.
- 6. The measurement system measured the field strength at the reference location.
- 7. Measurements at 2mm increments in the 5 x 5 cm region were performed at a distance 1 cm from the probe elements to the WD. A 360° rotation about the azimuth axis at the maximum interpolated position was measured. For the worst-case condition, the peak reading from this rotation was used in re-evaluating the HAC category.
- 8. The system performed a drift evaluation by measuring the field at the reference location.
- 9. Steps 1-8 were done for both the E and H-Field measurements.

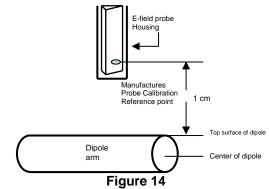
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7. SYSTEM CHECK

I. System Check Parameters

The input signal was an un-modulated continuous wave. The following points were taken into consideration in performing this check:

- Average Input Power P = 100mW RMS (20dBm RMS) after adjustment for return loss
- The test fixture must meet the 2 wavelength separation criterion
- The proper measurement of the 1 cm probe to dipole separation, which is measured from top surface
 of the dipole to the calibration reference point of the sensor, defined by the probe manufacturer is
 shown in the following diagram:



Separation Distance from Dipole to Field Probe

RF power was recorded using both an average reading meter and a peak reading meter. Readings of the probe are provided by the measurement system.

To assure proper operation of the near-field measurement probe the input power to the dipole shall be commensurate with the full rated output power of the wireless device (e.g. - for a cellular phone wireless device the average peak antenna input power will be on the order of 100mW (i.e. - 20dBm) RMS after adjustment for any mismatch.

II. Validation Procedure

A dipole antenna meeting the requirements given in PC63.19 was placed in the position normally occupied by the WD.

The length of the dipole was scanned with both E-field and H-field probes and the maximum values for each were recorded.

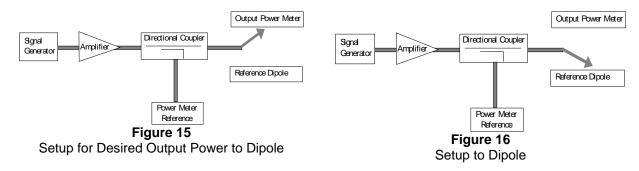
Measurement of CW

Using the near-field measurement system, scan the antenna over the radiating dipole and record the greatest field reading observed. Due to the nature of E-fields about free-space dipoles, the two E-field peaks measured over the dipole are averaged to compensate for non-parallelity of the setup (

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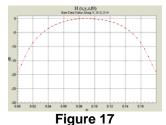
see manufacturer method on dipole calibration certificates, page 2). Field strength measurements shall be made only when the probe is stationary.

RF power was recorded using both an average and a peak power reading meter.

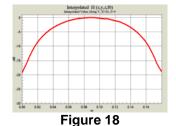


Using this setup configuration, the signal generator was adjusted for the desired output power (100mW) at a specified frequency. The reference power from the coupled port of the directional coupler is recorded. Next, the output cable is connected to the reference dipole, as shown in Figure 16.

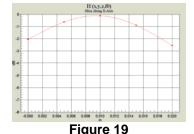
The input signal level was adjusted until the reference power from the coupled port of the directional coupler was the same as previously recorded, to compensate for the impedance mismatch between the output cable and the reference dipole. To assure proper operation of the near-field measurement probe the input power to the reference dipole was verified to the full rated output power of the wireless device. The dipole was secured in a holder in a manner to meet the 20 dB reflection. The near-field measurement probe was positioned over the dipole. The antenna was scanned over the appropriate sized area to cover the dipole from end to end. SPEAG uses 2D interpolation algorithms between the measured points. Please see below two dimensional plots showing that the interpolated values interpolate smoothly between 5mm steps for a free-space RF dipole:



2-D Raw Data from scan along dipole axis



2-D Interpolated points from scan along dipole axis



2-D Raw Data from scan along transverse axis



2-D Interpolated points from scan along transverse axis

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III. System Check Results

Validation Results

Frequency (MHz)	Input Power (dBm)	E-field Result (V/m)	Target Field (V/m)	% Deviation
835	20.0	175.7	185.1	-5.1%
1880	20.0	149.0	145.8	2.2%
Frequency (MHz)	Input Power (dBm)	H-field Result (A/m)	Target Field (A/m)	% Deviation
	Power	Result	Field	, ,

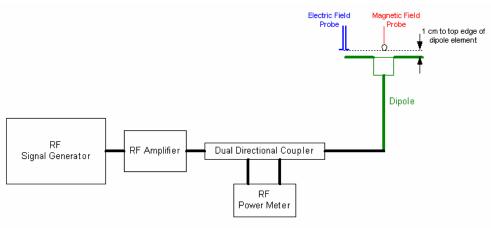


Figure 21 System Check Setup

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8. MODULATION FACTOR

A calibration was made of the modulation response of the probe and its instrumentation chain. This calibration was performed with the field probe, attached to its instrumentation. The response of the probe system to a CW field at the frequency of interest is compared to its response to a modulated signal with equal peak amplitude to that of a CW signal. The field level of the test signals are ensured to be more than 10 dB above the ambient level and the noise floor of the instrumentation being used. The ratio of the CW reading to that taken with a modulated reading was applied to the DUT measurements.

This was done using the following procedure:

- 1. The probe was illuminated with a CW signal at the intended measurement frequency.
- 2. The probe was positioned at the field maxima over the dipole antenna (determined after an area scan over the dipole).
- 3. The reading of the probe measurement system of the CW signal at the maximum point was recorded.
- 4. Using a Spectrum Analyzer, the modulated signal adjusted with the same peak level of the CW signal was determined.
- 5. The probe measurement system reading was recorded with the modulated signal. The appropriate system crest factors for the modulation type were configured in the software to the system measurements.
- 6. The ratio of the CW reading to modulated signal reading is the probe modulation factor (PMF) for the modulation and field probe combination.
- 7. Steps 1-6 were repeated at all frequency bands and for both E and H field probes.

The modulation factors obtained were applied to readings taken of the actual wireless device, in order to obtain an accurate peak field reading using the formula:

$$Peak = 20 \cdot log (Raw \cdot PMF)$$

This method correlates well with the modulation using the DUT in the alternative substitution method. See below for correlation of signal:

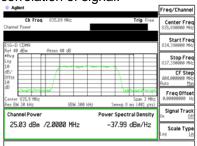


Figure 22 Signal Generator Modulated Signal



Figure 23
Wireless Device Modulated Signal

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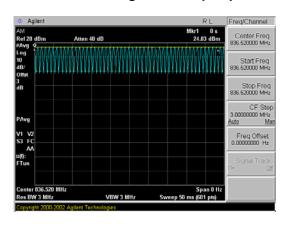
Modulation Factors:

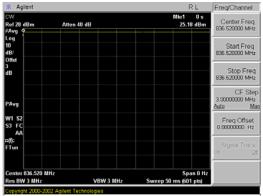
f (MHz)	Protocol	E-Field (V/m)	H-Field (A/m)	E-Field Modulation Factor	H-Field Modulation Factor
835	AM	219.2	0.6684	1.317	1.184
835	CDMA	311	0.9799	0.928	0.808
835	CW	288.6	0.7915		
1880	AM	155.4	0.6561	1.445	1.187
1880	CDMA	226.8	1.201	0.990	0.649
1880	CW	224.5	0.7789		

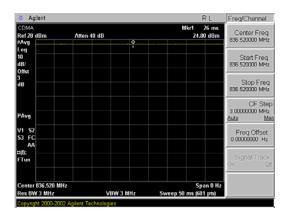
	f (MHz)	Protocol	E-Field (V/m)	H-Field (A/m)	E-Field Modulation Factor	H-Field Modulation Factor
ĺ	835	CDMA / SO3	72.27	0.2347	2.848	1.992
ľ	835	CW	205.8	0.4675		

Figure 24
Modulation Factors

CW and Modulated Signal Zero-Span plots:







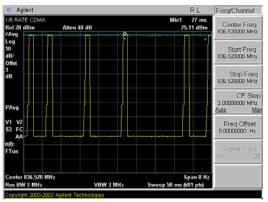


Figure 25 Zero-Span Plots

PCTEST™ HAC REPORT	PCTEST	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
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9. OVERALL MEASUREMENT SUMMARY

FCC ID:	A3LSPHA640S
Model:	SPH-A640S
S/N:	AD-004-A

I. E-FIELD EMISSIONS:

Table 1
HAC Data Summary for E-field

Th to bata dammar,								1014				
Mode	Channel	Backlight	so	Battery	Antenna	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Peak Field (dBV/m)	FCC Limit (dBV/m)	FCC MARGIN (dB)	RESULT	Excl Blocks per 4.3.1.2.2
E-field Em	issions											
CDMA	1013	off	SO2	Standard	Fixed	25.40	79.1	37.3	41.0	-3.69	М3	none
CDMA	384	off	SO2	Standard	Fixed	25.10	86.3	38.1	41.0	-2.93	М3	none
CDMA	777	off	SO2	Standard	Fixed	25.40	94.8	38.9	41.0	-2.11	М3	none
PCS	25	off	SO2	Standard	Fixed	25.20	37.1	31.3	41.0	-9.71	M4	none
PCS	600	off	SO2	Standard	Fixed	25.20	36.0	31.0	41.0	-9.96	M4	none
PCS	1175	off	SO2	Standard	Fixed	25.50	30.0	29.4	41.0	-11.56	M4	none
CDMA	777	on	SO2	Standard	Fixed	25.40	107.9	40.0	41.0	-0.99	M3	none
CDMA	777	on	SO3	Standard	Fixed	25.40	35.4	39.7	41.0	-1.34	M3	none

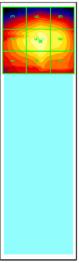


Figure 26
Sample E-field Scan Overlay
(See Test Setup Photographs for actual WD overlay)

Note: Worst-case measurement evaluated for worst-case 1/8 rate gating condition in RC1/SO3; Backlight=off, Mute=Yes

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FCC ID:	A3LSPHA640S
Model:	SPH-A640S
S/N:	AD-004-A

II. H-FIELD EMISSIONS:

Table 2
HAC Data Summary for H-field

Mode	Channel	Backlight	so	Battery	Antenna	Conducted Power at BS (dBm)	Time Avg. Field (A/m)	Peak Field (dBA/m)	FCC Limit (dBA/m)	FCC MARGIN (dB)	RESULT	Excl Blocks per 4.3.1.2.2
H-field Em	issions											
CDMA	1013	off	SO2	Standard	Fixed	25.40	0.109	-21.1	-9.4	-11.70	M4	none
CDMA	384	off	SO2	Standard	Fixed	25.10	0.121	-20.2	-9.4	-10.78	M4	none
CDMA	777	off	SO2	Standard	Fixed	25.40	0.151	-18.3	-9.4	-8.87	M4	none
PCS	25	off	SO2	Standard	Fixed	25.20	0.100	-23.7	-9.4	-14.33	M4	none
PCS	600	off	SO2	Standard	Fixed	25.20	0.092	-24.5	-9.4	-15.13	M4	none
PCS	1175	off	SO2	Standard	Fixed	25.50	0.093	-24.4	-9.4	-15.04	M4	none

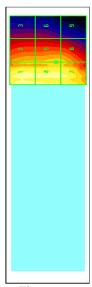


Figure 27
Sample H-field Scan Overlay
(See Test Setup Photographs for actual WD overlay)

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FCC ID:	A3LSPHA640S
Model:	SPH-A640S
S/N:	AD-004-A

III. Worst-case Configuration Evaluation

Table 3
Peak Reading 360° Probe Rotation at Azimuth axis

Mode	Channel	Backlight	so	Battery	Antenna	Conducted Power at BS (dBm)	Time Avg. Field (V/m)	Peak Field (dBV/m)	FCC Limit (dBV/m)	FCC MARGIN (dB)	RESULT
Probe Rotat	Probe Rotation at Worst-case										
CDMA	777	on	SO2	Standard	Fixed	25.40	110.4	40.2	41.0	-0.79	M3

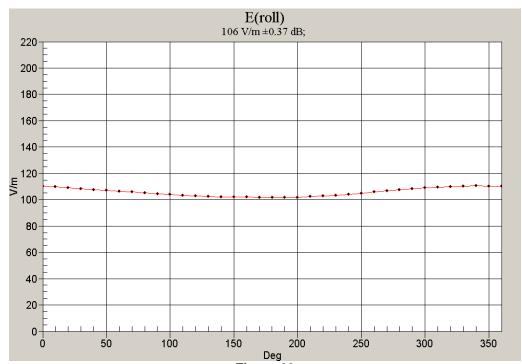


Figure 28
Worst-Case Probe Rotation about Azimuth axis

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^{*} Note: Location of probe rotation is shown in Figure 26 or Figure 27

10. EQUIPMENT LIST

Manufacturer	Make / Equipment	Calibration Due	Asset No.
HP	437B Power Meter	May 2006	3125U24437
Amplifier Research	5S1G4 (5W, 800MHz-4.2GHz)	January 2007	22322
Gigatronics	80701A (0.05-18GHz) Power Sensor	April 2006	1833460
HP	8482H (30mW-3W) Power Sensor	February 2007	2237A02084
HP	8594A Spectrum Analyzer	February 2007	3051A00187
Gigatronics	8657A Universal Power Meter	April 2006	1835256
HP	8753E (30kHz-6GHz) Network Analyzer	February 2007	JP38020182
Agilent	8960 Base Station Simulator	January 2007	PCT080
Agilent	Base Station Simulator	May 2006	661
Rohde & Schwarz	CMD80 Base Station Simulator	June 2006	830805/005
Rohde & Schwarz	CMU200 Base Station Simulator	October 2006	650378
Agilent	ESG-D Signal Generator	October 2006	PCT800
Optix	Fiber-Optic Line	N/A	
SPEAG	Freespace 1880 MHz Dipole	February 2007	1002
SPEAG	Freespace 1900 MHz Dipole	February 2007	1002
SPEAG	Freespace 2450 MHz Dipole	February 2007	1004
SPEAG	Freespace H-field Probe	August 2006	6170
SPEAG	Freespace E-field Probe	August 2006	2353
Bruel & Kjaer	HATS System	January 2007	687
Hosa	High Precision TRS Cable	N/A	
EMCO	Model 3115 (1-18GHz) Horn Antenna	October 2006	9203-2178
EMCO	Model 3115 (1-18GHz) Horn Antenna	October 2006	9704-5182
Rohde & Schwarz	NRVS Power Meter	June 2006	
RF Lindgren Model 26- 2/2-0	Shielded Screen Room	N/A	6710 (PCT270)
MicroCoax	(1.0-26.5GHz) Microwave Cables	N/A	N/A
HP	8648D (9kHz-4GHz) Signal Generator	October 2006	3613A00315
Rohde & Schwarz	(0.1-1000MHz) Signal Generator	September 2006	894215/012
Ray Proof Model S81	Shielded Semi-Anechoic Chamber	N/A	R2437 (PCT278)
Narda	3020A (50-1000MHz) Bi-Directional Coax Coupler	January 2007	
HP	8901A Modulation Analyzer	January 2007	2432A03467
HP	8903B Audio Analyzer	January 2007	3011A09025

Table 4Equipment List

*Calibration traceable to the National Institute of Standards and Technology (NIST).

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11. MEASUREMENT UNCERTAINTY

Wireless Co	Wireless Communications Device Near-Field Measurement					
	Und	ertainty Esti	mation			
Uncertainty Component	Data (dB)	Data Type	Prob. Dist.	Divisor	Unc. (dB)	Notes/Comments
easurement System						
RF System Reflections	0.50	Tolerance	R	1.73	0.30	* Refl. < -20 dB
RF Ambient Conditions	0.20	Tolerance	R	1.73	0.12	
Field Probe Conversion Factor	0.42	Tolerance	R	1.73	0.25	
Field Probe Isotropy	0.11	Tolerance	R	1.73	0.06	
Field Probe Frequency Response	0.135	Tolerance	R	1.73	0.08	
Field Probe Linearity	0.025	Tolerance	R	1.73	0.01	
Boundary Effects	0.105	Accuracy	R	1.73	0.06	
Sensor Displacement	0.66	Accuracy	R	1.73	0.39	*
Probe Positioning Accuracy	0.20	Accuracy	R	1.73	0.12	*
Probe Positioner	0.050	Accuracy	R	1.73	0.03	*
Extrapolation/Interpolation	0.045	Tolerance	R	1.73	0.03	*
System Detection Limit	0.05	Tolerance	R	1.73	0.03	*
Readout Electronics	0.015	Tolerance	N	1.00	0.02	*
Integration Time	0.11	Tolerance	R	1.73	0.06	*
Response Time	0.033	Tolerance	R	1.73	0.02	*
Phantom Thickness	0.10	Tolerance	R	1.73	0.06	*
Test Sample Related						
Device Positioning Vertical	0.4	Tolerance	R	1.73	0.24	*
Device Positioning Lateral	0.045	Tolerance	N	1	0.05	*
Device Holder and Phantom	0.1	Tolerance	R	1.73	0.06	*
Power Drift	0.21	Tolerance	N	1	0.21	
Combined Standard Uncertainty (k=1)	Combined Standard Uncertainty (k=1)					16.1%
Expanded Uncertainty (k=2) [95% confidence]				1.30	32.3%	

Table 5Uncertainty Estimation Table

Notes:

- Test equipments are calibrated according to techniques outlined in NIS81, NIS3003 and NIST Tech Note 1297. All
 equipments have traceability according to NIST. Measurement Uncertainties are defined in further detail in NIS 81
 and NIST Tech Note 1297 and UKAS M3003.
- 2. * Uncertainty specifications from Schmidt & Partner Engineering AG (not site specific)

Measurement uncertainty reflects the quality and accuracy of a measured result as compared to the true value. Such statements are generally required when stating results of measurements so that it is clear to the intended audience that the results may differ when reproduced by different facilities. Measurement results vary due to the measurement uncertainty of the instrumentation, measurement technique, and test engineer. Most uncertainties are calculated using the tolerances of the instrumentation used in the measurement, the measurement setup variability, and the technique used in performing the test. While not generally included, the variability of the equipment under test also figures into the overall measurement uncertainty. Another component of the overall uncertainty is based on the variability of repeated measurements (so-called Type A uncertainty). This may mean that the Hearing Aid immunity tests may have to be repeated by taking down the test setup and resetting it up so that there are a statistically significant number of repeat measurements to identify the measurement uncertainty. By combining the repeat measurement results with that of the instrumentation chain using the technique contained in NIS 81 and NIS 3003, the overall measurement uncertainty was estimated.

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12. TEST DATA

See following Attached Pages for Test Data.

PCTEST™ HAC REPORT	PCTEST.	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
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DUT: HAC Dipole 835 MHz

Type: CD835V3 Serial: 1003

Communication System: CW; Frequency: 835 MHz;

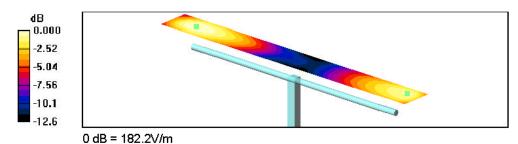
Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 SN2353; Calibrated: 8/2/2005
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 8/8/2005
- Phantom: HAC; Type: SD HAC P01 BA;
- Measurement SW: DASY4, V4.6 Build 23;

835MHz, 100mW/20dBm/Hearing Aid Compatibility Test (41x361x1):

Measurement grid: dx=5mm, dy=5mm
Reference Value = 117.4 V/m; Power Drift = 0.041 dB
Average value of Total (interpolated) = 182.2 V/m



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DUT: HAC Dipole 1900 MHz

Type: CD1880V3 Serial: 1002

Communication System: CW; Frequency: 1880 MHz;

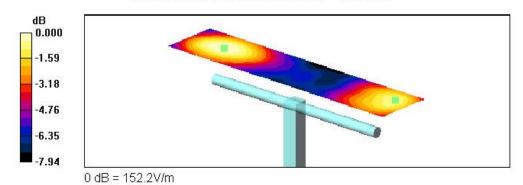
Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 SN2353; Calibrated: 8/2/2005
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 8/8/2005
- Phantom: HAC; Type: SD HAC P01 BA;
- Measurement SW: DASY4, V4.6 Build 23;

1880MHz, 100mW/20dBm/Hearing Aid Compatibility Test (41x181x1):

Measurement grid: dx=5mm, dy=5mm
Reference Value = 145.7 V/m; Power Drift = -0.002 dB
Average value of Total (interpolated) = 152.2 V/m



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DUT: HAC Dipole 835 MHz

Type: CD835V3 Serial: 1003

Communication System: CW; Frequency: 835 MHz;

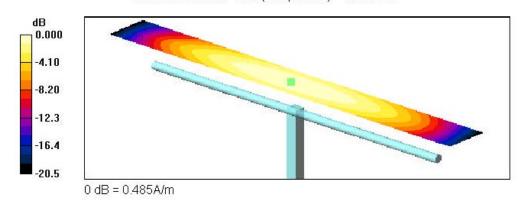
Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 SN6170; Calibrated: 8/8/2005
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 8/8/2005
- Phantom: HAC; Type: SD HAC P01 BA;
- Measurement SW: DASY4, V4.6 Build 23;

835MHz, 100mW/20dBm/Hearing Aid Compatibility Test (41x361x1):

Measurement grid: dx=5mm, dy=5mm
Reference Value = 0.516 A/m; Power Drift = 0.070 dB
Maximum value of Total (interpolated) = 0.485 A/m



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DUT: HAC Dipole 1900 MHz

Type: CD1880V3 Serial: 1002

Communication System: CW; Frequency: 1880 MHz;

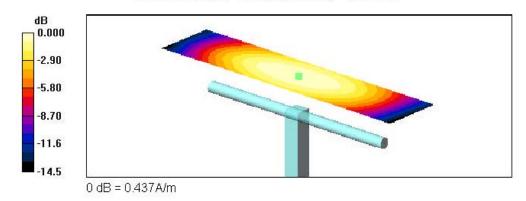
Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 SN6170; Calibrated: 8/8/2005
- Sensor-Surface: 0mm (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 8/8/2005
- Phantom: HAC; Type: SD HAC P01 BA;
- Measurement SW: DASY4, V4.6 Build 23;

1880MHz, 100mW/20dBm/Hearing Aid Compatibility Test (101x451x1):

Measurement grid: dx=2mm, dy=2mm
Reference Value = 0.457 A/m; Power Drift = -0.001 dB
Maximum value of Total (interpolated) = 0.437 A/m



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DUT: SPH-A640

Type: Dual-Band CDMA Phone Serial: AD-004-A Backlight on Duty Cycle: 1:1

Communication System: Cellular CDMA; Frequency: 848.31 MHz;

Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: ER3DV6 SN2353; Calibrated: 8/2/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 8/8/2005
- Phantom: HAC; Type: SD HAC P01 BA;
- . Measurement SW: DASY4, V4.6 Build 23;

High.ch BackLight On/Hearing Aid Compatibility Test (251x251x1):

Measurement grid: dx=2mm, dy=2mm
Maximum value of peak Total field = 100.1 V/m
Probe Modulation Factor = 0.928
Reference Value = 96.0 V/m; Power Drift = 1.04 dB
Hearing Aid Near-Field Category: M3 (AWF 0 dB)

Peak E-field in V/m

Grid 1	Grid 2	Grid 3
81.2	88.5	75.3
	Grid 5	
93.9	100.1	86.3
Grid 7	Grid 8	Grid 9
83.1	91.1	81.7



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HAC Filename:	Test Dates:	EUT Type:	FCC ID:	Page 31 of 70
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Date: 3/9/2006



DUT: SPH-A640

Type: Dual-Band CDMA Phone Serial: AD-004-A Backlight off Duty Cycle: 1:1

Communication System: PCS CDMA; Frequency: 1851.25 MHz;

Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

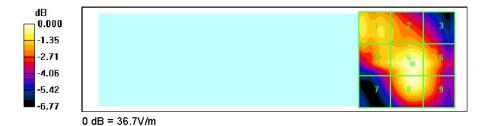
- Probe: ER3DV6 SN2353; Calibrated: 8/2/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 8/8/2005
- Phantom: HAC, Type: SD HAC P01 BA;
- Measurement SW: DASY4, V4.6 Build 23;

Low.ch/Hearing Aid Compatibility Test (251x251x1): Measurement grid: dx=2mm, dy=2mm

Maximum value of peak Total field = 36.7 V/m
Probe Modulation Factor = 0.990
Reference Value = 32.1 V/m; Power Drift = 0.098 dB
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

Peak E-field in V/m

Grid 2 30.2	
 Grid 5 36.7	
 Grid 8 35.7	



PCTEST™ HAC REPORT	FCC MEASUREMENT REPORT		SAMSUNG	Reviewed by: Quality Manager
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Date: 3/9/2006



DUT: SPH-A640

Type: Dual-Band CDMA Phone Serial: AD-004-A Backlight off Duty Cycle: 1:1

Communication System: Cellular CDMA; Frequency: 848.31 MHz;

Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

- Probe: H3DV6 SN6170; Calibrated: 8/8/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 8/8/2005
- Phantom: HAC; Type: SD HAC P01 BA;
- Measurement SW: DASY4, V4.6 Build 23;

High.ch/Hearing Aid Compatibility Test (251x251x1): Measurement grid: dx=2mm, dy=2mm

Maximum value of peak Total field = 0.122 A/m
Probe Modulation Factor = 0.808
Reference Value = 0.083 A/m; Power Drift = 0.624 dB
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

Peak H-field in A/m

Grid 2 0.092	1
 Grid 5 0.097	
 Grid 8 0.096	



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DUT: SPH-A640

Type: Dual-Band CDMA Phone Serial: AD-004-A Backlight off Duty Cycle: 1:1

Communication System: PCS CDMA; Frequency: 1851.25 MHz;

Measurement Standard: DASY4 (High Precision Assessment)

DASY4 Configuration:

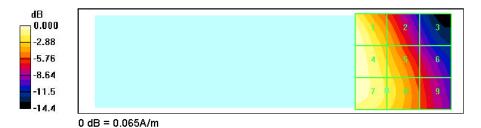
- Probe: H3DV6 SN6170; Calibrated: 8/8/2005
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn665; Calibrated: 8/8/2005
- Phantom: HAC; Type: SD HAC P01 BA;
- Measurement SW: DASY4, V4.6 Build 23;

Low.ch/Hearing Aid Compatibility Test (251x251x1): Measurement grid: dx=2mm, dy=2mm

Maximum value of peak Total field = 0.065 A/m
Probe Modulation Factor = 0.649
Reference Value = 0.058 A/m; Power Drift = -0.036 dB
Hearing Aid Near-Field Category: M4 (AWF 0 dB)

Peak H-field in A/m

 Grid 2 0.042	
 Grid 5 0.049	
 Grid 8 0.051	



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13. CALIBRATION CERTIFICATES

The following pages include the probe calibration used to evaluate HAC for the DUT.

PCTEST™ HAC REPORT	PCTEST:	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
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Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland



S Schweizerlscher Kalibrierdienst
Service sulsse d'étalonnage
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S Swiss Calibration Service

Accredited by the Swiss Federal Office of Metrology and Accreditation
The Swiss Accreditation Service is one of the signatories to the EA
Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 108

Cllent

PC Test

Certificate No: ER3-2353_Aug05

Object	ER3DV6 - SN:2	353	
Calibration procedure(s)	QA CAL-02:v4 Calibration proc evaluations in al	edure for E-field probes optimized for r	close near field
Calibration date:	August 2, 2005		
Condition of the calibrated item	In Tolerance		
The measurements and the unce	rtainties with confidence	tional standards, which realize the physical units of probability are given on the following pages and are ory facility: environment temperature (22 ± 3)°C and	e part of the certificate.
Calibration Equipment used (M&	i E critical for calibration)		
	ID#	Cai Date (Calibrated by, Certificate No.)	Scheduled Calibration
Primary Standards	1	Cal Date (Calibrated by, Certificate No.) 3-May-05 (METAS, No. 251-00466)	Scheduled Calibration May-06
Primary Standards Power meter E4419B	ID#		
Primary Standards Power meter E4419B Power sensor E4412A	ID # GB41293874	3-May-05 (METAS, No. 251-00466)	May-06
rrimary Standards Fower meter E4419B Fower sensor E4412A Fower sensor E4412A	ID # GB41293874 MY41495277	3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466)	May-06 May-06
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator	ID # GB41293874 MY41495277 MY41498087	3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466)	May-06 May-06 May-06
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c)	3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 10-Aug-04 (METAS, No. 251-00403)	May-06 May-06 May-06 Aug-05
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b)	3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 10-Aug-04 (METAS, No. 251-00403) 3-May-05 (METAS, No. 251-00467)	May-06 May-06 May-06 Aug-05 May-06
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b)	3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 10-Aug-04 (METAS, No. 251-00403) 3-May-05 (METAS, No. 251-00467) 10-Aug-04 (METAS, No. 251-00404)	May-06 May-06 May-06 Aug-05 May-06 Aug-05
Primary Standards Power meter E44198 Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 20 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 2328	3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 10-Aug-04 (METAS, No. 251-00403) 3-May-05 (METAS, No. 251-00407) 10-Aug-04 (METAS, No. 251-00404) 6-Oct-04 (SPEAG, No. ER3-2328_Oct04) 7-Jul-05 (SPEAG, No. DAE4-617_Jul05) Check Date (in house)	May-06 May-06 May-06 Aug-05 May-06 Aug-05 Oct-05 Jul-06 Scheduled Check
Primary Standards Power meter E4419B Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 20 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards RF generator HP 8648C	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 2328 SN: 617 ID # US3642U01700	3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 10-Aug-04 (METAS, No. 251-00403) 3-May-05 (METAS, No. 251-00407) 10-Aug-04 (METAS, No. 251-00404) 6-Oct-04 (SPEAG, No. ER3-2328_Oct04) 7-Jul-05 (SPEAG, No. DAE4-617_Jul05) Check Date (in house) 4-Aug-99 (SPEAG, in house check Dec-03)	May-06 May-06 May-06 Aug-05 May-06 Aug-05 Oct-05 Jul-06 Scheduled Check In house check: Dec-05
Primary Standards Power meter E44198 Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 20 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards RF generator HP 8648C	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 2328 SN: 617	3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 10-Aug-04 (METAS, No. 251-00403) 3-May-05 (METAS, No. 251-00407) 10-Aug-04 (METAS, No. 251-00404) 6-Oct-04 (SPEAG, No. ER3-2328_Oct04) 7-Jul-05 (SPEAG, No. DAE4-617_Jul05) Check Date (in house)	May-06 May-06 May-06 Aug-05 May-06 Aug-05 Oct-05 Jul-06 Scheduled Check
Primary Standards Power meter E44198 Power sensor E4412A Power sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 20 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards RF generator HP 8648C	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 2328 SN: 617 ID # US3642U01700	3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 10-Aug-04 (METAS, No. 251-00403) 3-May-05 (METAS, No. 251-00407) 10-Aug-04 (METAS, No. 251-00404) 6-Oct-04 (SPEAG, No. ER3-2328_Oct04) 7-Jul-05 (SPEAG, No. DAE4-617_Jul05) Check Date (in house) 4-Aug-99 (SPEAG, in house check Dec-03) 18-Oct-01 (SPEAG, in house check Nov-04)	May-06 May-06 May-06 Aug-05 May-06 Aug-05 Oct-05 Jul-06 Scheduled Check In house check: Dec-05
Primary Standards Prower meter E4419B Prower sensor E4412A Prower sensor E4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference Probe ER3DV6 PAE4 Recondary Standards RF generator HP 8648C Retwork Analyzer HP 8753E	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 2328 SN: 617 ID # US3642U01700 US37390585	3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 10-Aug-04 (METAS, No. 251-00403) 3-May-05 (METAS, No. 251-00467) 10-Aug-04 (METAS, No. 251-00404) 6-Oct-04 (SPEAG, No. ER3-2328_Oct04) 7-Jul-05 (SPEAG, No. DAE4-617_Jul05) Check Date (in house) 4-Aug-99 (SPEAG, in house check Dec-03) 18-Oct-01 (SPEAG, in house check Nov-04)	May-06 May-06 May-06 Aug-05 May-06 Aug-05 Oct-05 Jul-06 Scheduled Check In house check: Dec-05 In house check: Nov 05
Primary Standards Power meter E44198 Power sensor E4412A Power sensor E4412A Power sensor e4412A Reference 3 dB Attenuator Reference 20 dB Attenuator Reference 30 dB Attenuator Reference Probe ER3DV6 DAE4	ID # GB41293874 MY41495277 MY41498087 SN: S5054 (3c) SN: S5086 (20b) SN: S5129 (30b) SN: 2328 SN: 617 ID # US3642U01700 US37390585 Name	3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466) 10-Aug-04 (METAS, No. 251-00403) 3-May-05 (METAS, No. 251-00407) 10-Aug-04 (METAS, No. 251-00404) 6-Oct-04 (SPEAG, No. ER3-2328_Oct04) 7-Jul-05 (SPEAG, No. DAE4-617_Jul05) Check Date (in house) 4-Aug-99 (SPEAG, in house check Dec-03) 18-Oct-01 (SPEAG, in house check Nov-04)	May-06 May-06 May-06 Aug-05 May-06 Aug-05 Oct-05 Jul-06 Scheduled Check In house check: Dec-05 In house check: Nov 05

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Calibration Laboratory of

Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland



S Schweizerlscher Kallbrierdlenst
C Service sulsse d'étalonnage
Servizio svizzero di taratura
S Swiss Calibration Service

Accredited by the Swiss Federal Office of Metrology and Accreditation
The Swiss Accreditation Service is one of the signatories to the EA
Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 108

Glossary:

NORMx,y,z sensitivity in free space
DCP diode compression point
Polarization φ rotation around probe axis

Polarization 9 9 rotation around an axis that is in the plane normal to probe axis (at

measurement center), i.e., 9 = 0 is normal to probe axis

Connector Angle information used in DASY system to align probe sensor X to the robot

coordinate system

Calibration is Performed According to the Following Standards:

a) IEEE Std 1309-1996, "IEEE Standard for calibration of electromagnetic field sensors and probes, excluding antennas, from 9 kHz to 40 GHz", 1996.

Methods Applied and Interpretation of Parameters:

- NORMx,y,z: Assessed for E-field polarization 9 = 0 for XY sensors and 9 = 90 for Z sensor (f ≤ 900 MHz in TEM-cell; f > 1800 MHz: R22 waveguide).
- NORM(f)x,y,z = NORMx,y,z * frequency_response (see Frequency Response Chart).
- DCPx,y,z: DCP are numerical linearization parameters assessed based on the data of power sweep (no uncertainty required). DCP does not depend on frequency.
- Spherical isotropy (3D deviation from isotropy): in a locally homogeneous field realized using an open waveguide setup.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- Connector Angle: The angle is assessed using the information gained by determining the NORMx (no uncertainty required).

1000

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Probe ER3DV6

SN:2353

Manufactured: March 8, 2005 Calibrated: August 2, 2005

Calibrated for DASY Systems

(Note: non-compatible with DASY2 system!)

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DASY - Parameters of Probe: ER3DV6 SN:2353

Sensitivity in Free Space $[\mu V/(V/m)^2]$ Diode (

Diode Compression^A

NormX	1.55 ± 10.1 % (k=2)	DCP X	95 mV
NormY	1.73 ± 10.1 % (k=2)	DCP Y	95 mV
NormZ	1.86 ± 10.1 % (k=2)	DCP Z	96 mV

Frequency Correction

X	0.0
Υ	0.0
Z	0.0

Sensor Offset

(Probe Tip to Sensor Center)

X 2.5 mm Y 2.5 mm Z 2.5 mm

Connector Angle

29°

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

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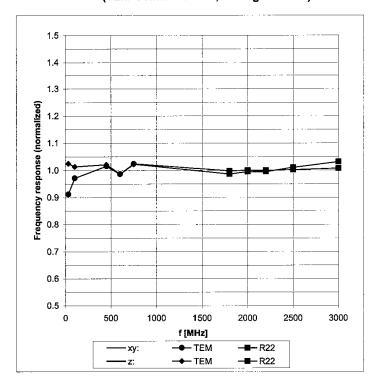
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^A numerical linearization parameter: uncertainty not required

Frequency Response of E-Field

(TEM-Cell:ifi110 EXX, Waveguide R22)



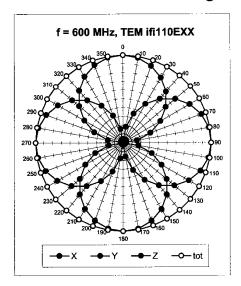
Uncertainty of Frequency Response of E-field: \pm 6.3% (k=2)

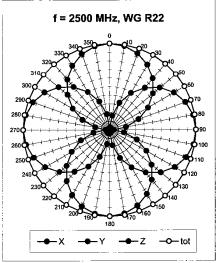
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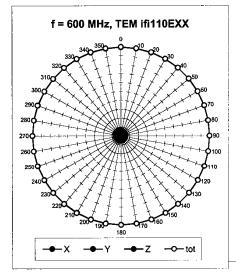
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HAC Filename:	Test Dates:	EUT Type:	FCC ID:	Page 40 of 70
HAC.0602210101.A3L	March 9 - 10, 2006	Dual-Band CDMA Phone	A3LSPHA640S	Faye 40 01 70

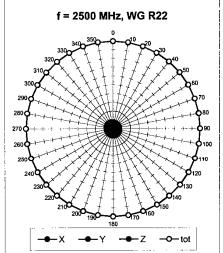
Receiving Pattern (ϕ), ϑ = 0°





Receiving Pattern (ϕ), $\vartheta = 90^{\circ}$



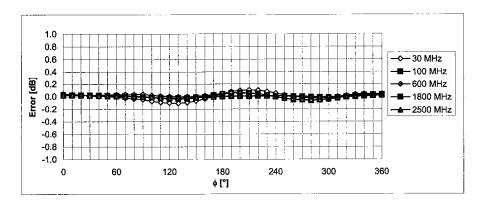


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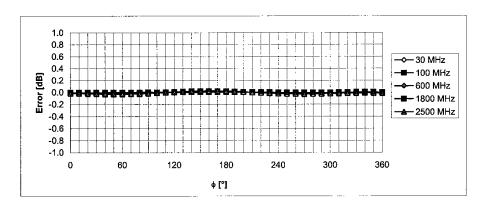
PCTEST™ HAC REPORT	PCTEST	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
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Receiving Pattern (ϕ), ϑ = 0°



Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

Receiving Pattern (ϕ), $\vartheta = 90^{\circ}$



Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

Certificate No: ER3-2353_Aug05

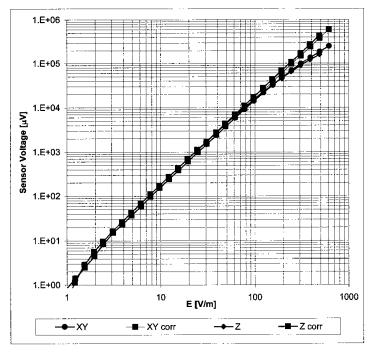
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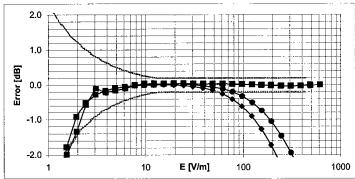
PCTEST™ HAC REPORT	PCTEST:	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
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August 2, 2005

Dynamic Range f(E-field)

(Waveguide R22, f = 1800 MHz)





Uncertainty of Linearity Assessment: ± 0.6% (k=2)

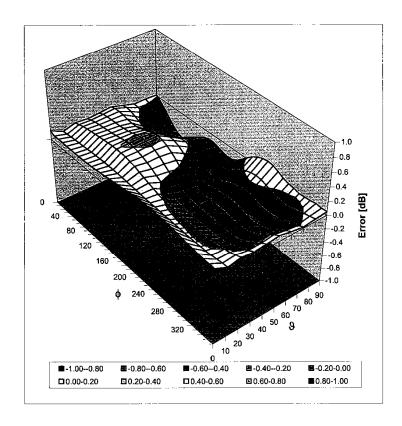
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Deviation from Isotropy in Air Error (ϕ , ϑ) , f = 900 MHz



Uncertainty of Spherical Isotropy Assessment: ± 2.6% (k=2)

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Calibration Laboratory of Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland



S Schwelzerischer Kalibrierdienst
C Service sulsse d'étalonnage
Servizio svizzero di taratura
S Swiss Calibration Service

Accredited by the Swiss Federal Office of Metrology and Accreditation The Swiss Accreditation Service is one of the signatories to the EA Multilateral Agreement for the recognition of calibration certificates Accreditation No.: SCS 108

Client PC Test Certificate No: H3-6170_Aug05

Reference Probe H3DV6 DAE4 Secondary Standards RF generator HP 8648C Network Analyzer HP 8753E Calibrated by: Approved by:	SN: 617 ID # US3642U01700 US37390585 Name Katja Pokovic	Check Date (in house) 4-Aug-99 (SPEAG, in house check Dec-03) 18-Oct-01 (SPEAG, in house check Nov-04) Function Technical Manager	Scheduled Check In house check: Dec-05 In house check: Nov 05 Signature
DAE4 Secondary Standards RF generator HP 8648C Network Analyzer HP 8753E	ID # US3642U01700 US37390585	Check Date (in house) 4-Aug-99 (SPEAG, in house check Dec-03) 18-Oct-01 (SPEAG, in house check Nov-04) Function	In house check: Dec-05 In house check: Nov 05
DAE4 Secondary Standards RF generator HP 8648C Network Analyzer HP 8753E	ID # US3642U01700 US37390585	Check Date (in house) 4-Aug-99 (SPEAG, in house check Dec-03) 18-Oct-01 (SPEAG, in house check Nov-04) Function	In house check: Dec-05 In house check: Nov 05
Secondary Standards RF generator HP 8648C	ID # US3642U01700 US37390585	Check Date (in house) 4-Aug-99 (SPEAG, in house check Dec-03) 18-Oct-01 (SPEAG, in house check Nov-04)	In house check: Dec-05 In house check: Nov 05
Secondary Standards Figenerator HP 8648C	ID # US3642U01700	Check Date (in house) 4-Aug-99 (SPEAG, in house check Dec-03)	In house check: Dec-05
AE4 econdary Standards	ID # US3642U01700	Check Date (in house) 4-Aug-99 (SPEAG, in house check Dec-03)	
AE4	ID#	Check Date (in house)	Scheduled Check
	SN: 617	. 64, 66 (6. 2 (6, 116, 27.2) 6166.66)	
	SN: 617		Jul-00
eference Probe H3DV6		7-Jul-05 (SPEAG, No. DAE4-617 Jul05)	Jul-06
Olbuilany on on Augundinie	SN: 6182	6-Oct-04 (SPEAG, No. H3-6182 Oct04)	Oct-05
telerence 20 dB Attenuator	SN: S5006 (20b)	10-Aug-04 (METAS, No. 251-00404)	Aug-05
teference 3 dB Attenuator	SN: S5086 (20b)	3-May-05 (METAS, No. 251-00405)	May-05 May-06
ower sensor E44 (ZA Reference 3 dB Attenuator	SN: S5054 (3c)	3-May-05 (METAS, No. 251-00466) 10-Aug-04 (METAS, No. 251-00403)	Aug-05
ower sensor E4412A lower sensor E4412A	MY41495277 MY41498087		мау-0 6 Мау-06
ower meter E44198 ower sensor E4412A	MY41495277	3-May-05 (METAS, No. 251-00466) 3-May-05 (METAS, No. 251-00466)	May-06
rimary Standards	ID # GB41293874	Cal Date (Calibrated by, Certificate No.) 3-May-05 (METAS, No. 251-00466)	Scheduled Calibration May-06
Calibration Equipment used (M&			0-1
All calibrations have been conduc	cted in the closed laborat	ory facility: environment temperature (22 ± 3)°C and	d humidity < 70%.
The measurements and the unit	Training with confidence	probability are given on the following pages and are	per or the confined.
	-	ational standards, which realize the physical units of probability are given on the following pages and are	
Condition of the calibrated item	In Tolerance		
Calibration date:	August 8, 2005		
	araidations III d		
Salibration procedure(3)	A STATE OF THE PARTY OF THE PAR	edure for H-field probes optimized for	close near field
Calibration procedure(s)	QA CAL-03.v4		
	1100 10. 011.01		i distriction (1965), desperator (1961) (1965) Secretaria (1965) (1965) (1965) (1965)
Dbject	H3DV6 - SN:61	to the content of the reserve of the content of the	The state of the s

Certificate No: H3-6170_Aug05

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PCTEST™ HAC REPORT	PCTEST	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
HAC Filename:	Test Dates:	EUT Type:	FCC ID:	Page 45 of 70
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Calibration Laboratory of

Schmid & Partner Engineering AG Zeughausstrasse 43, 8004 zurich, Switzerland



S Schweizerischer Kallbrierdienst
C Service sulsse d'étalonnage
Servizio svizzero di taratura
S Swiss Calibration Service

Accredited by the Swiss Federal Office of Metrology and Accreditation
The Swiss Accreditation Service is one of the signatories to the EA
Multilateral Agreement for the recognition of calibration certificates

Accreditation No.: SCS 108

Glossary:

NORMx,y,z sensitivity in free space diode compression point Polarization φ rotation around probe axis

Polarization ϑ ϑ rotation around an axis that is in the plane normal to probe axis (at

measurement center), i.e., 9 = 0 is normal to probe axis

Connector Angle information used in DASY system to align probe sensor X to the robot

coordinate system

Calibration is Performed According to the Following Standards:

a) IEEE Std 1309-1996, "IEEE Standard for calibration of electromagnetic field sensors and probes, excluding antennas, from 9 kHz to 40 GHz", 1996.

Methods Applied and Interpretation of Parameters:

- X,Y,Z_a0a1a2: Assessed for E-field polarization θ = 90 for XY sensors and θ = 0 for Z sensor (f ≤ 900 MHz in TEM-cell; f > 1800 MHz: R22 waveguide).
- X,Y,Z(f)_a0a1a2= X,Y,Z_a0a1a2* frequency_response (see Frequency Response Chart).
- DCPx,y,z: DCP are numerical linearization parameters assessed based on the data of power sweep (no uncertainty required). DCP does not depend on frequency.
- Spherical isotropy (3D deviation from isotropy): in a locally homogeneous field realized using an open waveguide setup.
- Sensor Offset: The sensor offset corresponds to the offset of virtual measurement center from the probe tip (on probe axis). No tolerance required.
- Connector Angle: The angle is assessed using the information gained by determining the X a0a1a2 (no uncertainty required).

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Probe H3DV6

SN:6170

Manufactured: Calibrated:

May 19, 2005 August 8, 2005

Calibrated for DASY Systems

(Note: non-compatible with DASY2 system!)

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DASY - Parameters of Probe: H3DV6 SN:6170

Sensitivity in Free Space [A/m / √(μV)]

	a0 a	ı1 a	a2
X	2.502E-03	1.072E-4	-3.021E-6 ± 5.1 % (k=2)
Υ	2.645E-03	2.739E-6	-2.811E-5 ± 5.1 % (k=2)
7	2.960E-03	-6.594E-5	2.809E-5 ± 5.1 % (k=2)

Diode Compression¹

DCP X	85 mV
DCP Y	85 mV
DCP Z	86 mV

Sensor Offset (Probe Tip to Sensor Center)

X 3.0 mm Y 3.0 mm Z 3.0 mm

Connector Angle

29°

The reported uncertainty of measurement is stated as the standard uncertainty of measurement multiplied by the coverage factor k=2, which for a normal distribution corresponds to a coverage probability of approximately 95%.

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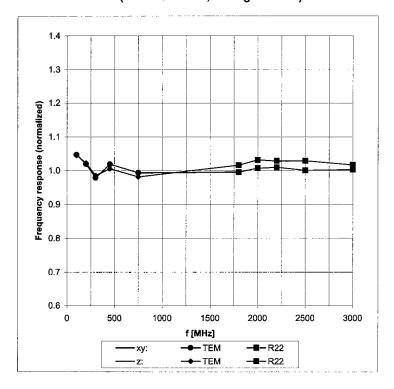
Page 4 of 8

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¹ numerical linearization parameter: uncertainty not required

Frequency Response of H-Field

(TEM-Cell:ifi110, Waveguide R22)



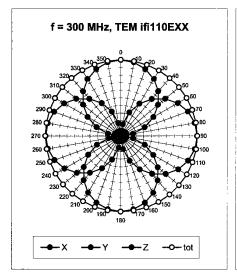
Uncertainty of Frequency Response of E-field: ± 6.3% (k=2)

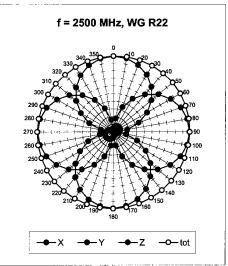
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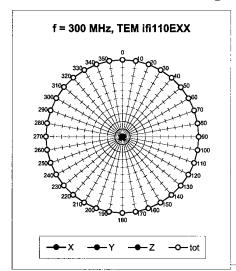
PCTEST™ HAC REPORT	PCTEST	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
HAC Filename:	Test Dates:	EUT Type:	FCC ID:	Page 49 of 70
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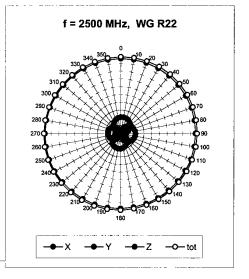
Receiving Pattern (ϕ), ϑ = 90°





Receiving Pattern (ϕ), $\vartheta = 0^{\circ}$



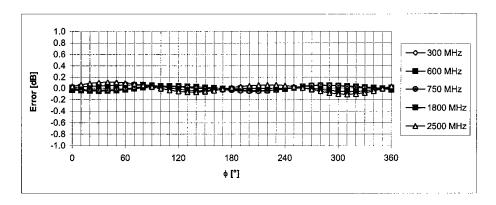


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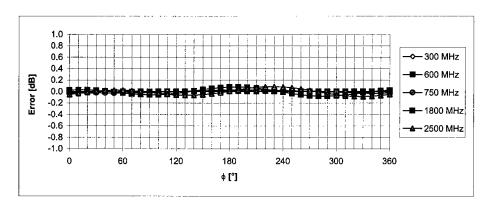
PCTEST™ HAC REPORT	PCTEST	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
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Receiving Pattern (ϕ), $\vartheta = 90^{\circ}$



Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

Receiving Pattern (ϕ), $9 = 0^{\circ}$



Uncertainty of Axial Isotropy Assessment: ± 0.5% (k=2)

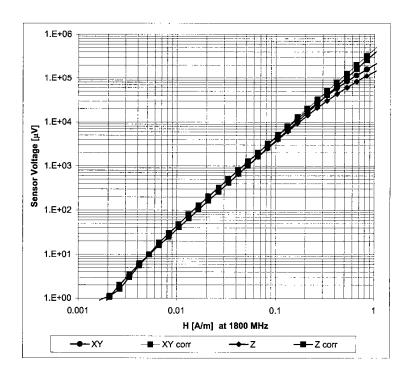
Certificate No: H3-6170_Aug05

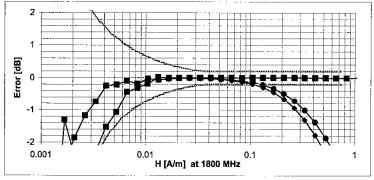
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PCTEST™ HAC REPORT	PCTEST	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
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Dynamic Range f(H-field)

(Waveguide R22, f = 1800 MHz)





Uncertainty of Linearity Assessment: ± 0.6% (k=2)

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Calibration Laboratory of

Schmid & Partner

Engineering AG Zeughausstrasse 43, 8004 Zurich, Switzerland

Client

Certificate No: CD1880V3-1002_Feb05

Object	CD1880V3 - SN:	1002	i 1971 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982 - 1982
Calibration procedure(s)	QA CAL-20.v2 Calibration proce	dure for dipoles in air.	
Calibration date:	February, 23, 200	05	
Condition of the calibrated item	In Tolerance		
This calibration certificate docum All calibrations have been condu Calibration Equipment used (M&	cted in the closed laborator	onal standards, which realize the physical units of y facility: environment temperature (22 ± 3)°C and	measurements (SI). d humidity < 70%.
Calibration Equipment used (Ma	TE Official for Campidation)		
Primary Standards	ID#	Cal Date (Calibrated by, Certificate No.)	Scheduled Calibration
, ,		Cal Date (Calibrated by, Certificate No.) 12-Oct-04 (METAS, No. 251-00412)	Scheduled Calibration Oct-05
Primary Standards Power meter EPM E442	ID#		
Primary Standards Power meter EPM E442 Power sensor HP 8481A	ID # GB37480704	12-Oct-04 (METAS, No. 251-00412)	Oct-05
Primary Standards Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator	ID # GB37480704 US37292783	12-Oct-04 (METAS, No. 251-00412) 12-Oct-04 (METAS, No. 251-00412)	Oct-05 Oct-05
Primary Standards Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator	ID # GB37480704 US37292783 SN: 5086 (20g)	12-Oct-04 (METAS, No. 251-00412) 12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05
Primary Standards Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator Reference Probe ER3DV6	ID # GB37480704 US37292783 SN: 5086 (20g) SN: 5047.2 (10r)	12-Oct-04 (METAS, No. 251-00412) 12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402)	Oct-05 Oct-05 Aug-05 Aug-05
Primary Standards	ID # GB37480704 US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328	12-Oct-04 (METAS, No. 251-00412) 12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05
Primary Standards Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards	ID # GB37480704 US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601	12-Oct-04 (METAS, No. 251-00412) 12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06
Primary Standards Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards Power sensor HP 8481A	ID# GB37480704 US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601	12-Oct-04 (METAS, No. 251-00412) 12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06 Scheduled Check
Primary Standards Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards Power sensor HP 8481A Power sensor HP 8481A	ID # GB37480704 US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601 ID # MY41092312	12-Oct-04 (METAS, No. 251-00412) 12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05) Check Date (in house) 10-Aug-03 (SPEAG, in house check Jan-04)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06 Scheduled Check In house check: Oct-05 In house check: Aug-05
Primary Standards Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards Power sensor HP 8481A Power sensor HP 8481A RF generator Agilent E8251A	ID # GB37480704 US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601 ID # MY41092312 MY41093315	12-Oct-04 (METAS, No. 251-00412) 12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05) Check Date (in house) 10-Aug-03 (SPEAG, in house check Jan-04) 10-Aug-03 (SPEAG, in house check Jan-04)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06 Scheduled Check In house check: Oct-05 In house check: Oct-05 In house check: Aug-05 In house check: Nov-05
Primary Standards Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards Power sensor HP 8481A Power sensor HP 8481A RF generator Agilent E8251A Network Analyzer HP 8753E	ID # GB37480704 US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601 ID # MY41092312 MY41093315 US41140111	12-Oct-04 (METAS, No. 251-00412) 12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05) Check Date (in house) 10-Aug-03 (SPEAG, in house check Jan-04) 10-Aug-03 (Agilent)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06 Scheduled Check In house check: Oct-05 In house check: Aug-05
Primary Standards Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator Reference Probe ER3DV6 DAE4 Secondary Standards Power sensor HP 8481A Power sensor HP 8481A RF generator Agilent E8251A Network Analyzer HP 8753E	ID # GB37480704 US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601 ID # MY41092312 MY41093315 US41140111 US37390585 S4206	12-Oct-04 (METAS, No. 251-00412) 12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05) Check Date (in house) 10-Aug-03 (SPEAG, in house check Jan-04) 10-Aug-03 (Agilent) 18-Oct-01 (SPEAG, in house check Nov-04)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06 Scheduled Check In house check: Oct-05 In house check: Oct-05 In house check: Aug-05 In house check: Nov-05
Primary Standards Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator Reference Probe ER3DV6 DAE4	ID # GB37480704 US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601 ID # MY41092312 MY41093315 US41140111 US37390585 S4206 SN: 6065	12-Oct-04 (METAS, No. 251-00412) 12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05) Check Date (in house) 10-Aug-03 (SPEAG, in house check Jan-04) 10-Aug-03 (SPEAG, in house check Jan-04) 4-Aug-03 (Agilent) 18-Oct-01 (SPEAG, in house check Nov-04) 10-Oct-04 (SPEAG, No. H3-6065-Oct04)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06 Scheduled Check In house check: Oct-05 In house check: Oct-05 In house check: Aug-05 In house check: Nov-05 Calibration, Oct-05

This calibration certificate is issued as an intermediate solution until the specific calibration procedure is submitted and accepted in the frame of the accreditation of the Calibration Laboratory of Schmid & Partner Engineering AG (based on ISO/IEC 17025 International Standard)

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Calibration Laboratory of Schmid & Partner

Engineering AG

Zeughausstrasse 43, 8004 Zurich, Switzerland

References

[1] ANSI-PC63.19-2003 (Draft)

American National Standard for Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna
 (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes.
 In coincidence with standard [1], the measurement planes (probe sensor center) are selected to be at a
 distance of 10 mm above the the top edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All
 figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector
 is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a
 directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY4 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network
 Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was
 eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any
 obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 10 mm (in z) above the top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, 10mm above the dipole surface.
- H-field distribution: H-field is measured with an isotropic H-field probe with 100mW forward power to the
 antenna feed point, in the x-y-plane. The scan area and sensor distance is equivalent to the E-field scan. The
 maximum of the field is available at the center (subgrid 5) above the feed point. The H-field value stated as
 calibration value represents the maximum of the interpolated H-field, 10mm above the dipole surface at the
 feed point.

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1 Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY4	V4.5 B13
DASY PP Version	SEMCAD	V1.8 B144
Phantom	HAC Test Arch	SD HAC P01 BA, #1002
Distance Dipole Top - Probe Center	10 mm	
Scan resolution	dx, dy = 5 mm	area = 20 x 90 mm
Frequency	1880 MHz ± 1 MHz	
Forward power at dipole connector	20.0 dBm = 100mW	
Input power drift	< 0.05 dB	

2 Maximum Field values

H-field 10 mm above dipole surface	condition	interpolated maximum
Maximum measured	100 mW forward power	0.450 A/m

Uncertainty for H-field measurement: 19.5% (k=2)

E-field 10 mm above dipole surface	condition	interpolated maximum
Maximum measured above high end	100 mW forward power	146.0 V/m
Maximum measured above low end	100 mW forward power	145.6 V/m
Averaged maximum above arm	100 mW forward power	145.8 V/m

Uncertainty for E-field measurement: 21.7% (k=2)

3 Appendix

3.1 Antenna Parameters

Frequency	Return Loss	Impedance
1710 MHz	23.4 dB	(55.2 + j6.1) Ohm
1880 MHz	21.4 dB	(53.9 + j7.4) Ohm
1900 MHz	20.9 dB	(55.8 + j6.7) Ohm
1950 MHz	28.0 dB	(54.1 + j1.9) Ohm
2000 MHz	18.9 dB	(51.2 + j11.9) Ohm

3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

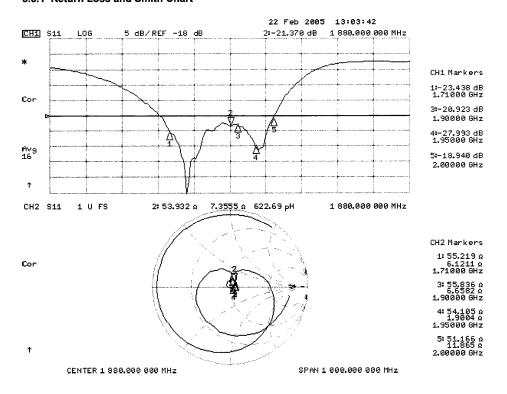
Certificate No: CD1880V3-1002_Feb05

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3.3 Measurement Sheets

3.3.1 Return Loss and Smith Chart



3.3.2 DASY4 H-field result

See page 5

3.3.3 DASY4 E-Field result

See page 6

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HAC Filename:	Test Dates:	EUT Type:	FCC ID:	Page 56 of 70
HAC.0602210101.A3L	March 9 - 10, 2006	Dual-Band CDMA Phone	A3LSPHA640S	rage 30 01 70

Date/Time: 23.02.2005 11:02:39

Test Laboratory: SPEAG, Zurich, Switzerland File Name: H CD1880 1002 050223.da4

DUT: HAC Dipole 1880 MHz; Type: CD1880V3; Serial: 1002 Program Name: HAC H Dipole

Communication System: CW; Frequency: 1880 MHz; Duty Cycle: 1:1 Medium parameters used: $\sigma = 0$; mho/m, $\varepsilon_r = 1$; $\rho = 1 \text{ kg/m}^3$

Phantom section: H Dipole Section

DASY4 Configuration:

- Probe: H3DV6 SN6065; ; Calibrated: 10.12.2004
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn901; Calibrated: 29.06.2004
- Phantom: HAC Phantom; Type: SD HAC P01 BA;
 Measurement SW: DASY4, V4.5 Build 13; Postprocessing SW: SEMCAD, V1.8 Build 144

H Scan 10mm above CD 1880 MHz/Hearing Aid Compatibility Test (41x181x1): Measurement grid: dx=5mm,

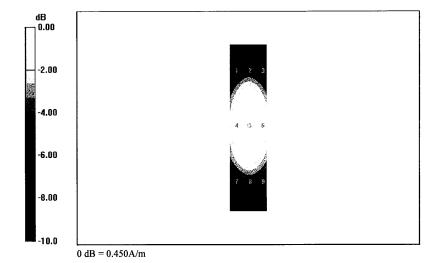
dy=5mm, dz=5.5555mm

Maximum value of Total field (slot averaged) = 0.450 A/m

Hearing Aid Near-Field Category: M2 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3			Grid 3
0.385	0.413	0.395	0.385	0.413	0.395
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
0.421	0.450	0.432	0.421	0.450	0.432
	Grid 8				Grid 9
0.376	0.401	0.386	0.376	0.401	0.386



PCTEST™ HAC REPORT	PCTEST	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
HAC Filename:	Test Dates:	EUT Type:	FCC ID:	Page 57 of 70
HAC 0602210101 A3I	March 9 - 10, 2006	Dual-Band CDMA Phone	431 SPH4640S	Fage 57 01 70

Test Laboratory: SPEAG, Zurich, Switzerland File Name; E. CD1880_1002_050223.da4

DUT: HAC Dipole 1880 MHz; Type: CD1880V3; Serial: 1002

Program Name: HAC E Dipole

Communication System: CW; Frequency: 1880 MHz;Duty Cycle: 1:1 Medium parameters used: σ = 0; mho/m, ϵ_r = 1; ρ = 1000 kg/m³

Phantom section: E Dipole Section

DASY4 Configuration:

- Probe: ER3DV6 SN2328; ConvF(1, 1, 1); Calibrated: 06.10.2004
- Sensor-Surface: (Fix Surface)
- Electronics; DAE4 Sn901; Calibrated: 29.06.2004 - Phantom: HAC Phantom; Type; SD HAC P01 BA;
- Measurement SW: DASY4, V4.5 Build 13; Postprocessing SW: SEMCAD, V1.8 Build 144

E Scan 10mm above CD 1880 MHz/Hearing Aid Compatibility Test (41x181x1): Measurement grid: dx=5mm,

dy=5mm, dz=5.5555mm

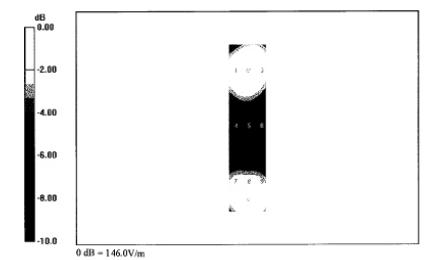
Maximum value of Total field (slot averaged) = 146.0 V/m

Hearing Aid Near-Field Category: M2 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

Grid 1	Grid 2:	Grid 3
128.7	145.6	130.5
Grid 4	Grid 5	Grid 6
90.1	92.4	88.8
	92.4 Grid 8	

Grid 1 128.7	Grid 2 145.6	
	Grid 5 92.4	
	Grid 8 146.0	



PCTEST™ HAC REPORT	PCTEST:	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
HAC Filename:	Test Dates:	EUT Type:	FCC ID:	Page 58 of 70
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Calibration Laboratory of

Schmid & Partner Engineering AG

Zeughausstrasse 43, 8004 Zurich, Switzerland

Client

PC TEST

Certificate No. CD835V3-1003 Feb05

Calibration procedure(s)			
	QA CAL-20:v2 Calibration proce	dure for dipoles in air.	
Calibration date:	February, 23, 20	95 ************************************	
Condition of the calibrated item	In Tolerance		
Calibration Equipment used (M8 Primary Standards	TE critical for calibration)	Cal Date (Calibrated by, Certificate No.)	Scheduled Calibration
minuty Claridates			
	GB37480704	12-Oct-04 (METAS, No. 251-00412)	Oct-05
ower meter EPM E442	GB37480704 US37292783	12-Oct-04 (METAS, No. 251-00412) 12-Oct-04 (METAS, No. 251-00412)	
ower meter EPM E442 ower sensor HP 8481A		,	Oct-05 Oct-05 Aug-05
Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator	US37292783 SN: 5086 (20g) SN: 5047.2 (10r)	12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402)	Oct-05 Oct-05 Aug-05 Aug-05
Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator Reference Probe ER3DV6	US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328	12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05
ower meter EPM E442 lower sensor HP 8481A deference 20 dB Attenuator deference 10 dB Attenuator deference Probe ER3DV6	US37292783 SN: 5086 (20g) SN: 5047.2 (10r)	12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402)	Oct-05 Oct-05 Aug-05 Aug-05
Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator Reference Probe ER3DV6 DAE4	US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328	12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05
rower meter EPM E442 rower sensor HP 8481A reference 20 dB Attenuator reference 10 dB Attenuator reference Probe ER3DV6 reference Probe ER3DV6 reference Standards	US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601	12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06
rower meter EPM E442 rower sensor HP 8481A reference 20 dB Attenuator reference 10 dB Attenuator reference Probe ER3DV6 reference Probe ER3DV6 reference Standards reference Standards reference PR 8481A	US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601	12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06 Scheduled Check
Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator Reference Probe ER3DV6 DAE4 Recondary Standards Power sensor HP 8481A RF generator Agilent E8251A	US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601 ID # MY41092312	12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05) Check Date (in house) 10-Aug-03 (SPEAG, in house check Jan-04)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06 Scheduled Check In house check: Oct-05
Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator Reference Probe ER3DV6 DAE4 Recondary Standards Power sensor HP 8481A Power sensor HP 8481A	US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601 ID # MY41092312 MY41093315	12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05) Check Date (in house) 10-Aug-03 (SPEAG, in house check Jan-04) 10-Aug-03 (SPEAG, in house check Jan-04)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06 Scheduled Check In house check: Oct-05 In house check: Oct-05
Power meter EPM E442 Power sensor HP 8481A Reference 20 dB Attenuator Reference 10 dB Attenuator Reference Probe ER3DV6 DAE4 Recondary Standards Power sensor HP 8481A RF generator Agilent E8251A	US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601 ID # MY41092312 MY41093315 US41140111	12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05) Check Date (in house) 10-Aug-03 (SPEAG, in house check Jan-04) 10-Aug-03 (Agilent)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06 Scheduled Check In house check: Oct-05 In house check: Aug-05
rower meter EPM E442 rower sensor HP 8481A reference 20 dB Attenuator reference 10 dB Attenuator reference Probe ER3DV6 rower sensor HP 8481A rower sensor HP 8481A rower sensor HP 8481A reference Agilent E8251A reference PM 8481A rower sensor HP 8481A	US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601 ID # MY41092312 MY41093315 US41140111 US37390585 S4206	12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05) Check Date (in house) 10-Aug-03 (SPEAG, in house check Jan-04) 10-Aug-03 (Agilent) 18-Oct-01 (SPEAG, in house check Nov-04)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06 Scheduled Check In house check: Oct-05 In house check: Oct-05 In house check: Aug-05 In house check: Nov-05
ower meter EPM E442 lower sensor HP 8481A leference 20 dB Attenuator leference 10 dB Attenuator leference Probe ER3DV6 lAE4 lecondary Standards lower sensor HP 8481A lower sensor HP 8481A letwork Analyzer HP 8753E	US37292783 SN: 5086 (20g) SN: 5047.2 (10r) SN 2328 SN 601 ID # MY41092312 MY41093315 US41140111 US37390585 S4206 SN: 6066	12-Oct-04 (METAS, No. 251-00412) 10-Aug-04 (METAS, No 251-00402) 10-Aug-04 (METAS, No 251-00402) 06-Oct-04 (SPEAG, No. ER3-2328_Oct04) 07-Jan-05 (SPEAG, No. DAE4-601_Jan05) Check Date (in house) 10-Aug-03 (SPEAG, in house check Jan-04) 10-Aug-03 (SPEAG, in house check Jan-04) 4-Aug-03 (Agilent) 18-Oct-01 (SPEAG, in house check Nov-04) 10-Oct-04 (SPEAG, No. H3-6065-Oct04)	Oct-05 Oct-05 Aug-05 Aug-05 Oct-05 Jan-06 Scheduled Check In house check: Oct-05 In house check: Oct-05 In house check: Aug-05 In house check: Nov-05 Calibration, Oct-05

Issued: February 27, 200

This calibration certificate is issued as an intermediate solution until the specific calibration procedure is submitted and accepted in the frame of the accreditation of the Calibration Laboratory of Schmid & Partner Engineering AG (based on ISO/IEC 17025 International Standard)

Certificate No: CD835V3-1003_Feb05

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PCTEST™ HAC REPORT	FCC MEASUREMENT REPORT		SAMSUNG	Reviewed by: Quality Manager
HAC Filename:	Test Dates:	EUT Type:	FCC ID:	Page 59 of 70
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Calibration Laboratory of

Schmid & Partner **Engineering AG** Zeughausstrasse 43, 8004 Zurich, Switzerland

References

ANSI-PC63.19-2003 (Draft)

American National Standard for Methods of Measurement of Compatibility between Wireless Communications Devices and Hearing Aids.

Methods Applied and Interpretation of Parameters:

- Coordinate System: y-axis is in the direction of the dipole arms. z-axis is from the basis of the antenna (mounted on the table) towards its feed point between the two dipole arms. x-axis is normal to the other axes. In coincidence with standard [1], the measurement planes (probe sensor center) are selected to be at a distance of 10 mm above the top edge of the dipole arms.
- Measurement Conditions: Further details are available from the hardcopies at the end of the certificate. All figures stated in the certificate are valid at the frequency indicated. The forward power to the dipole connector is set with a calibrated power meter connected and monitored with an auxiliary power meter connected to a directional coupler. While the dipole under test is connected, the forward power is adjusted to the same level.
- Antenna Positioning: The dipole is mounted on a HAC Test Arch phantom using the matching dipole positioner with the arms horizontal and the feeding cable coming from the floor. The measurements are performed in a shielded room with absorbers around the setup to reduce the reflections. It is verified before the mounting of the dipole under the Test Arch phantom, that its arms are perfectly in a line. It is installed on the HAC dipole positioner with its arms parallel below the dielectric reference wire and able to move elastically in vertical direction without changing its relative position to the top center of the Test Arch phantom. The vertical distance to the probe is adjusted after dipole mounting with a DASY4 Surface Check job. Before the measurement, the distance between phantom surface and probe tip is verified. The proper measurement distance is selected by choosing the matching section of the HAC Test Arch phantom with the proper device reference point (upper surface of the dipole) and the matching grid reference point (tip of the probe) considering the probe sensor offset. The vertical distance to the probe is essential for the accuracy.
- Feed Point Impedance and Return Loss: These parameters are measured using a HP 8753E Vector Network Analyzer. The impedance is specified at the SMA connector of the dipole. The influence of reflections was eliminating by applying the averaging function while moving the dipole in the air, at least 70cm away from any obstacles.
- E-field distribution: E field is measured in the x-y-plane with an isotropic ER3D-field probe with 100 mW forward power to the antenna feed point. In accordance with [1], the scan area is 20mm wide, its length exceeds the dipole arm length (180 or 90mm). The sensor center is 10 mm (in z) above the top of the dipole arms. Two 3D maxima are available near the end of the dipole arms. Assuming the dipole arms are perfectly in one line, the average of these two maxima (in subgrid 2 and subgrid 8) is determined to compensate for any non-parallelity to the measurement plane as well as the sensor displacement. The E-field value stated as calibration value represents the maximum of the interpolated 3D-E-field, 10mm above the dipole surface.
- H-field distribution: H-field is measured with an isotropic H-field probe with 100mW forward power to the antenna feed point, in the x-y-plane. The scan area and sensor distance is equivalent to the E-field scan. The maximum of the field is available at the center (subgrid 5) above the feed point. The H-field value stated as calibration value represents the maximum of the interpolated H-field, 10mm above the dipole surface at the feed point.

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1 Measurement Conditions

DASY system configuration, as far as not given on page 1.

DASY Version	DASY4	V4.5 B13
DASY PP Version	SEMCAD	V1.8 B144
Phantom	HAC Test Arch	SD HAC P01 BA, #1002
Distance Dipole Top - Probe Center	10 mm	
Scan resolution	dx, dy = 5 mm	area = 20 x 180 mm
Frequency	835 MHz ± 1 MHz	
Forward power at dipole connector	20.0 dBm = 100mW	
Input power drift	< 0.05 dB	

2 Maximum Field values

H-field 10 mm above dipole surface	condition	interpolated maximum
Maximum measured	100 mW forward power	0.470 A/m

Uncertainty for H-field measurement: 19.5% (k=2)

E-field 10 mm above dipole surface	condition	interpolated maximum
Maximum measured above high end	100 mW forward power	187.0 V/m
Maximum measured above low end	100 mW forward power	183.2 V/m
Averaged maximum above arm	100 mW forward power	185.1 V/m

Uncertainty for E-field measurement: 21.7% (k=2)

3 Appendix

3.1 Antenna Parameters

Frequency	Return Loss	Impedance
800 MHz	16.6 dB	(40.5 - j9.6) Ohm
835 MHz	25.2 dB	(55.3 + j2.4) Ohm
900 MHz	16.6 dB	(52.7 - j15.2) Ohm
950 MHz	25.1 dB	(50.9 + j5.5) Ohm
960 MHz	17.2 dB	(61.0 + j10.9) Ohm

3.2 Antenna Design and Handling

The calibration dipole has a symmetric geometry with a built-in two stub matching network, which leads to the enhanced bandwidth.

The dipole is built of standard semirigid coaxial cable. The internal matching line is open ended. The antenna is therefore open for DC signals.

Do not apply force to dipole arms, as they are liable to bend. The soldered connections near the feedpoint may be damaged. After excessive mechanical stress or overheating, check the impedance characteristics to ensure that the internal matching network is not affected.

After long term use with 40W radiated power, only a slight warming of the dipole near the feedpoint can be measured.

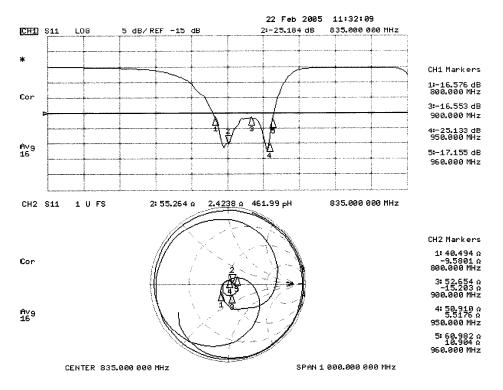
Page 3 of 6

Certificate No: CD835V3-1003_Feb05

PCTEST™ HAC REPORT	FCC MEASUREMENT REPORT		SAMSUNG	Reviewed by: Quality Manager
HAC Filename:	Test Dates:	EUT Type:	FCC ID:	Page 61 of 70
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3.3 Measurement Sheets

3.3.1 Return Loss and Smith Chart



3.3.2 DASY4 H-field result

See page 5

3.3.3 DASY4 E-Field result

See page 6

Certificate No: CD835V3-1003_Feb05

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PCTEST™ HAC REPORT	FCC MEASUREMENT REPORT		SAMSUNG	Reviewed by: Quality Manager
HAC Filename:	Test Dates:	EUT Type:	FCC ID:	Page 62 of 70
HAC.0602210101.A3L	March 9 - 10, 2006	Dual-Band CDMA Phone	A3LSPHA640S	Faye 02 01 70

Test Laboratory: SPEAG, Zurich, Switzerland File Name: H CD835 1003 050222.da4

DUT: HAC-Dipole 835 MHz; Type: D835V3; Serial: 1003

Program Name: HAC H Dipole

Communication System; CW; Frequency: 835 MHz; Duty Cycle: 1:1 Medium parameters used: σ = 0; mho/m, ϵ_{r} = 1; ρ = 1 kg/m³

Phantom section: H Dipole Section

DASY4 Configuration:

- Probe: H3DV6 SN6065; ; Calibrated: 10.12.2004
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn901; Calibrated: 29.06.2004
- Phantom: HAC Phantom; Type: SD HAC P01 BA; Serial: 1002
- Measurement SW: DASY4, V4.5 Build 13; Postprocessing SW: SEMCAD, V1.8 Build 144

H Scan 10mm above CD 835 MHz/Hearing Aid Compatibility Test (41x361x1): Measurement grid: dx=5mm,

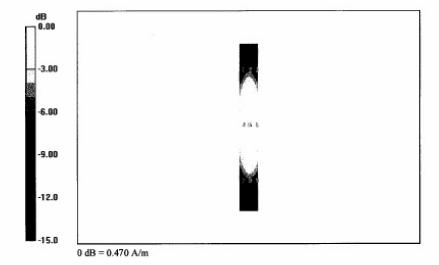
dy=5mm, dz=5.5555mm

Maximum value of Total field (slot averaged) = 0.470 A/m

Hearing Aid Near-Field Category: M2 (AWF 0 dB)

H in A/m (Time averaged) H in A/m (Slot averaged)

Grid 1	Grid 2	Grid 3	Grid 1	Grid 2	Grid 3
0.365	0.397	0.380	0.365	0.397	0.380
Grid 4	Grid 5	Grid 6	Grid 4	Grid 5	Grid 6
0.408	0.470	0.425	0.408	0.470	0.425
Grid 7	Grid 8	Grid 9	Grid 7	Grid 8	Grid 9
0.350	0.380	0.368	0.350	0.380	0.368



PCTEST™ HAC REPORT	FCC MEASUREMENT REPORT		SAMSUNG	Reviewed by: Quality Manager
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HAC.0602210101.A3L	March 9 - 10, 2006	Dual-Band CDMA Phone	A3LSPHA640S	Fage 03 01 70

Test Laboratory: SPEAG, Zurich, Switzerland File Name: E CD835 1003 050223.da4

DUT: HAC-Dipole 835 MHz; Type: D835V3; Serial: 1003 Program Name: HAC E Dipole

Communication System: CW; Frequency: 835 MHz; Duty Cycle: 1:1 Medium parameters used: $\sigma = 0$; mho/m, $\varepsilon_r = 1$; $\rho = 1000 \text{ kg/m}^3$

Phantom section: E Dipole Section

DASY4 Configuration:

- Probe; ER3DV6 SN2328; ConvF(1, 1, 1); Calibrated: 06.10.2004
- Sensor-Surface: (Fix Surface)
- Electronics: DAE4 Sn901; Calibrated: 29.06.2004
- Phantom: HAC Phantom; Type: SD HAC P01 BA; Serial: 1002
- Measurement SW: DASY4, V4.5 Build 13; Postprocessing SW: SEMCAD, V1.8 Build 144

E Scan 10mm above CD 835 MHz/Hearing Aid Compatibility Test (41x361x1): Measurement grid: dx=5mm,

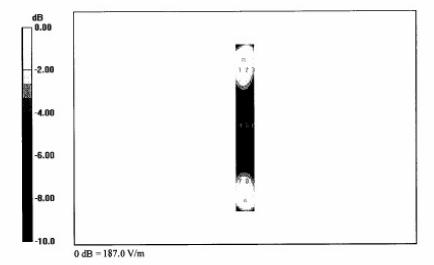
dy=5mm, dz=5.5555mm

Maximum value of Total field (slot averaged) = 187.0 V/m

Hearing Aid Near-Field Category: M2 (AWF 0 dB)

E in V/m (Time averaged) E in V/m (Slot averaged)

 Grid 2 187.0	Grid 3 150.1	Grid 1 156.0	
	Grid 6 80.4	Grid 4 83.6	
	Grid 9 149.5	Grid 7 148.0	



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14. CONCLUSION

The measurements indicate that the wireless communications device complies with the HAC limits specified in accordance with the ANSI PC63.19 Standard and FCC WT Docket No. 01-309 RM-8658. Precise laboratory measures were taken to assure repeatability of the tests. The tested device complies with the requirements in respect to all parameters specific to the test. The test results and statements relate only to the item(s) tested.

Please note that the M-rating for this equipment only represents the field interference possible against a hypothetical and typical hearing aid. The measurement system and techniques presented in this evaluation are proposed in the ANSI standard as a means of best approximating wireless device compatibility with a hearing-aid. The literature is under continual re-construction.

PCTEST™ HAC REPORT	PCTEST	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
HAC Filename:	Test Dates:	EUT Type:	FCC ID:	Page 65 of 70
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15. REFERENCES

- ANSI PC63.19-2005 D3.6, American National Standard for Methods of Measurement of Compatibility between Wireless communication devices and Hearing Aids.", New York, NY, IEEE, April 2005.
- 2. Berger, H. S., "Compatibility Between Hearing Aids and Wireless Devices," Electronic Industries Forum, Boston, MA, May, 1997
- 3. Berger, H. S., "Hearing Aid and Cellular Phone Compatibility: Working Toward Solutions," Wireless Telephones and Hearing Aids: New Challenges for Audiology, Gallaudet University, Washington, D.C., May, 1997 (To be reprinted in the American Journal of Audiology).
- 4. Berger, H. S., "Hearing Aid Compatibility with Wireless Communications Devices, " IEEE International Symposium on Electromagnetic Compatibility, Austin, TX, August, 1997.
- Bronaugh, E. L., "Simplifying EMI Immunity (Susceptibility) Tests in TEM Cells," in the 1990 IEEE International Symposium on Electromagnetic Compatibility Symposium Record, Washington, D.C., August 1990, pp. 488-491
- 6. Byme, D. and Dillon, H., The National Acoustics Laboratory (NAL) New Procedure for Selecting the Gain and Frequency Response of a Hearing Aid, Ear and Hearing 7:257-265, 1986.
- 7. Crawford, M. L., "Measurement of Electromagnetic Radiation from Electronic Equipment using TEM Transmission Cells, "U.S. Department of Commerce, National Bureau of Standards, NBSIR 73-306, Feb. 1973.
- 8. Crawford, M. L., and Workman, J. L., "Using a TEM Cell for EMC Measurements of Electronic Equipment," U.S. Department of Commerce, National Bureau of Standards. Technical Note 1013, July 1981.
- EHIMA GSM Project, Development phase, Project Report (1st part) Revision A. Technical-Audiological Laboratory and Telecom Denmark, October 1993.
- 10. EHIMA GSM Project, Development phase, Part II Project Report. Technical-Audiological Laboratory and Telecom Denmark, June 1994.
- 11. EHIMA GSM Project Final Report, Hearing Aids and GSM Mobile Telephones: Interference Problems, Methods of Measurement and Levels of Immunity. Technical-Audiological Laboratory and Telecom Denmark, 1995.
- 12. HAMPIS Report, Comparison of Mobile phone electromagnetic near field with an upscaled electromagnetic far field, using hearing aid as reference, 21 October 1999.
- 13. Hearing Aids/GSM, Report from OTWIDAM, Technical-Audiological Laboratory and Telecom Denmark, April 1993.
- 14. IEEE 100, The Authoritative Dictionary of IEEE Standards Terms, Seventh Edition.

PCTEST™ HAC REPORT	PCTEST:	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
HAC Filename:	Test Dates:	EUT Type:	FCC ID:	Page 66 of 70
HAC.0602210101.A3L	March 9 - 10, 2006	Dual-Band CDMA Phone	A3LSPHA640S	

- 15. Joyner, K. H, et. al., Interference to Hearing Aids by the New Digital Mobile Telephone System, Global System for Mobile (GSM) Communication Standard, National Acoustic Laboratory, Australian Hearing Series, Sydney 1993.
- 16. Joyner, K. H., et. al., Interference to Hearing Aids by the Digital Mobile Telephone System, Global System for Mobile Communications (GSM), NAL Report #131, National Acoustic Laboratory, Australian Hearing Series, Sydney, 1995.
- 17. Kecker, W. T., Crawford, M. L., and Wilson, W. A., "Contruction of a Transverse Electromagnetic Cell", U.S. Department of Commerce, National Bureau of Standards, Technical Note 1011, Nov. 1978.
- 18. Konigstein, D., and Hansen, D., "A New Family of TEM Cells with enlarged bandwidth and Optimized working Volume," in the Proceedings of the 7th International Symposium on EMC, Zurich, Switzerland, March 1987; 50:9, pp. 127-132.
- 19. Kuk, F., and Hjorstgaard, N. K., "Factors affecting interference from digital cellular telephones," Hearing Journal, 1997; 50:9, pp 32-34.
- 20. Ma, M. A., and Kanda, M., "Electromagnetic Compatibility and Interference Metrology," U.S. Department of Commerce, National Bureau of Standards, Technical Note 1099, July 1986, pp. 17-43.
- 21. Ma, M. A., Sreenivashiah, I., and Chang, D. C., "A Method of Determining the Emission and Susceptibility Levels of Electrically Small Objects Using a TEM Cell," U.S. Department of Commerce, National Bureau of Standards, Technial Note 1040, July 1981.
- 22. McCandless, G. A., and Lyregaard, P. E., Prescription of Gain/Output (POGO) for Hearing Aids, Hearing Instruments 1:16-21, 1983
- 23. Skopec, M., "Hearing Aid Electromagnetic Interference from Digital Wireless Telephones, "IEEE Transactions on Rehabilitation Engineering, vol. 6, no. 2, pp. 235-239, June 1998.
- 24. Technical Report, GSM 05.90, GSM EMC Considerations, European Telecommunications Standards Institute, January 1993.
- 25. Victorian, T. A., "Digital Cellular Telephone Interference and Hearing Aid Compatibility—an Update," Hearing Journal 1998; 51:10, pp. 53-60
- 26. Wong, G. S. K., and Embleton, T. F. W., eds., AIP Handbook of Condenser Microphones: Theory, Calibration and Measurements, AIP Press.

PCTEST™ HAC REPORT	PCTEST	FCC MEASUREMENT REPORT	SAMSUNG	Reviewed by: Quality Manager
HAC Filename:	Test Dates:	EUT Type:	FCC ID:	Page 67 of 70
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